AEDC-TR-12-F-6



How to Use Equipment Specifications to Predict Measurement Uncertainty

James L. Taylor Aerospace Testing Alliance

June 2012

Final Report for Period October 2011 - April 2012

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REPORT DOCUMENTATION PAGE			Form Approved OMB No. 0704-0188			
The public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing the burden, to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports (0704-0188), 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302. Respondents should be aware that notwithstanding any other provision of law, no person shall be subject to any penalty for failing to comply with a collection of information if it does not display a currently valid OMB control number. PLEASE DO NOT RETURN YOUR FORM TO THE ABOVE ADDRESS						
1. REPORT DATE (DD-MM-YYYY)	2. REPORT TYPE		3. DATES COVERED (From – To)			
xx-06-2012	Final Report		October 2011 – April 2012			
4. TITLE AND SUBTITLE		5a. CC	NTRACT NUMBER			
How to Use Equipment Specifications to Predict Measur	rement Uncertainty					
An Example Using Tunnels A, B and C Data System		5b. GF	RANT NUMBER			
		5c. PR	OGRAM ELEMENT NUMBER			
6. AUTHOR(S)		5d. PR	OJECT NUMBER			
Taylor, James L.			13218			
·		5e. TA	ASK NUMBER			
5f. W			ORK UNIT NUMBER			
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES)		•	8. PERFORMING ORGANIZATION REPORT NO.			
Arnold Engineering Development Center			KEI OKI NO.			
Air Force Materiel Command			AEDC-TR-12-F-6			
Arnold Air Force Base, TN 37389-6000						
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES)			10. SPONSOR/MONITOR'S ACRONYM(S)			
TSTW						
Building 740, 4th Street, Room 118			11. SPONSOR/MONITOR'S REPORT			
Arnold AFB, TN 37389-6000			NUMBER(S)			
12. DISTRIBUTION/AVAILABILITY STATEMENT						
Statement A: Approved for public release; distribution	unlimited					
13. SUPPLEMENTARY NOTES						
Available in the Defense Technical Information Center (DTIC).						
14. ABSTRACT						
This report illustrates a methodology for predicting data system measurement uncertainty using equipment specifications. The example presented is based on the data acquisition systems being built for Tunnels ABC. For this example, the measurement uncertainty is predicted for both voltage and force balance measurements. The analysis identified several error sources that could potentially prevent the system from meeting the requirements. Mitigation measures were identified that would enable the proposed system to meet the requirements.						

17. LIMITATION OF

ABSTRACT

Same as Report

18. NUMBER

49

OF PAGES

19A. NAME OF RESPONSIBLE PERSON

Simon Choi

19B. TELEPHONE NUMBER (Include area code)

931-454-3876

Standard Form 298 (Rev. 8/98) Prescribed by ANSI Std. 739.18

16. SECURITY CLASSIFICATION OF:

B. ABSTRACT

Unclassified

Measurement uncertainty, equipment manufacturer specifications

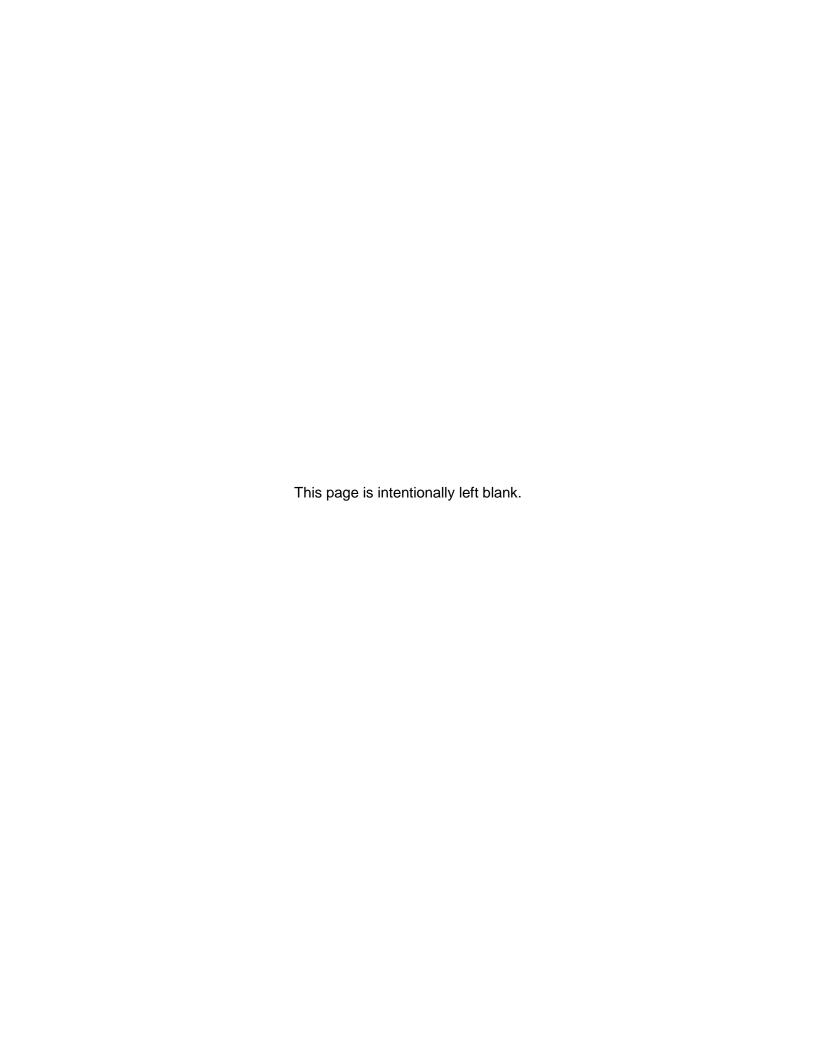
C. THIS PAGE

Unclassified

15. Subject Terms

A. REPORT

Unclassified



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1.0 INTRODUCTION

1.1 BACKGROUND

AEDC's test units use general purpose steady-state data acquisition systems to measure and acquire different phenomenon from the test articles being tested. This includes pressure, temperature, and force. A standard requirement is that the quality of the measured results must be quantified and provided to those who use the results. This enables others to compare the results (Ref. 1). AEDC uses the concept of measurement uncertainty to provide a quantifiable indication of the quality of measured results. For wind tunnel applications, the AIAA Standard S-071A-1999 (Ref 1) is used. For turbine engine applications, the ASME PTC 19.2-2005 (Ref 2) is used.

Historically, the measurement uncertainty for data acquisition systems has been experimentally determined after the system was installed and operational. An experiment is conducted wherein known inputs are applied at the system's input and the outputs recorded. Error sources such as the effects of temperature, time drift, and calibration interval are estimated and combined with experimentally determined errors to establish measurement uncertainty.

Over the years, experimental evaluation of uncertainty has largely gone by the wayside as a result of shrinking budgets. In its place, the system designer's estimate of measurement performance has been used. This estimate is based on interpretation of manufacturers' specifications and an understanding of the application. For this type evaluation, the individual parameter specifications or attributes (also referred to as errors) are combined using the Root Sum Square (RSS) method (Ref. 3). Predicting measurement uncertainty using manufacturers' specifications is considered a conservative approach with a major benefit of aiding in identifying error sources that can be mitigated through calibration or operational procedures. When funding is available, the predicted measurement uncertainty should be replaced or augmented with experimentally determined measurement uncertainty.

1.2 PURPOSE

The purpose of this document is to provide a current example that demonstrates how to predict a data system's measurement performance using manufacturers' specifications and, in so doing, point out mitigation techniques for some errors. The example is the new data acquisition system being built for AEDC's small wind tunnels — Tunnels A, B, and C.

2.0 STATEMENT OF THE PROBLEM AND METHOD OF ANALYSIS

2.1 PROBLEM STATEMENT

The problem in using equipment specifications to determine measurement uncertainty has two parts. First, interpreting the different manufacturers' performance specifications is difficult because there are no industry standards that provide manufacturer guidance in what attributes or parameters to include as part of their product's specifications. For example, two different manufacturers of comparable products can have entirely different specifications. Second, combining the different attributes into an estimate of measurement uncertainty is complicated because there are no standards that provide manufacturer guidance in how to quantify the different attributes. Manufacturers' specifications are subject to varying interpretations, leading to differences in the methods used to interpret specifications. This inconsistency could lead to a potentially flawed interpretation and an incorrect estimate of measurement uncertainty (Ref. 4).

The result could be that the system, when built and tested, fails to meet the requirements. Even so, the manufacturers' specifications represent the best estimator of performance, but they must be used with caution.

2.2 BACKGROUND

The new system will replace aged equipment and will be used as a general purpose data system. The system will be custom configured for each specific test. Since the system will be used to measure low-frequency or steady-state phenomena, the design emphasis is on performance, specifically measurement uncertainty. Bandwidth and sampling rate are requirements but are not included in this discussion. Also, sensor excitation in the form of either constant voltage or constant current is required for some of the different measurement types. Finally, all critical measurements at AEDC must be traceable to national standards. Since a large, multichannel system such as this must be calibrated in place as opposed to periodically transporting the system to a calibration laboratory for calibration, the system must include a National Institute of Science and Technology (NIST) traceable calibration standard that is used to calibrate the system in place and provide the required traceability.

It has been previously determined that the system will be designed as a multiplexed data system in which multiple inputs share a single analog-to-digital converter (ADC). To compensate for both noise and common mode voltage, each analog input will be configured using a differential amplifier for each channel and will include appropriate filtering to accommodate the different measurements. The multiplexer/ADC can be configured as a single-ended device since it is in close proximity to the amplifier outputs.

2.3 MEASUREMENT PERFORMANCE REQUIREMENTS

The measurement performance requirements for the critical force balance and voltage measurement types are listed below in Table 1. The requirement is that the uncertainty in the measured value will be less than the stated requirement to a probability of 95%. This is denoted as U_{95} .

Since the Tunnel ABC system will be a general purpose data acquisition system capable of acquiring data from various input devices, the standard practice is to establish the data acquisition system's measurement uncertainty independent of the input source. This allows the total measurement uncertainty for any specific measurement to be developed by combining the data system's measurement uncertainty with the measurement uncertainty of the input sensor or transducer. For example, to establish the total uncertainty for a measurement such as a load cell or force balance, the uncertainty of the data acquisition system would be combined with the uncertainty of the load cell or force balance using the RSS technique.

The measurement errors for both the general purpose voltage measurements and the force balance measurements are assumed to be normally distributed. This assumption is reflected in Table 1 below where the requirement for measurement uncertainty is stated in terms of 95% coverage or $\pm 2\sigma$ (Ref. 3). Since the system will be designed to accommodate a wide range of full scale input voltages, the accepted practice is to state uncertainty in terms of a percent as % FS. If FS is used, it must be defined such as FS = 10 mV or FS = x psia, etc. Since this is a replacement system, the threshold requirement in Table 1 represents the existing capability and is the minimum acceptable performance. In contrast, the objective requirement represents the desired performance assuming there is no impact on cost.

Table 1. Partial List of Tunnel A, B, C Measurement Requirements

Measurement	Threshold U ₉₅	Objective U ₉₅
General Purpose	±0.04%FS	±0.02%FS
Voltage		
Force Balance	±0.05%FS	±0.02%FS

2.4 APPROACH

The approach to establishing an estimate of measurement uncertainty is to identify equipment to meet each requirement. For example, the force balance requirement is ±0.05% FS on the 10-mV range. As a minimum, this will require a power supply to provide excitation to the force balance strain gauge, an amplifier to condition the low-level analog signal, and an analog-to-digital converter to convert the analog signal to digital format. The existing process used in other AEDC wind tunnels is to constantly measure the excitation voltage being applied to the force balance and to correct for any variations in the excitation. As a result, two separate data system channels are used for each force balance channel — one to measure the balance voltage and one to measure the applied excitation voltage or current. This is the approach used for the new data system force balance channels as well. All of the equipment (the two amplifiers, the excitation power supply, and the multiplexer/ADC) have elemental errors identified in the manufacturer's specifications that contribute to the total measurement uncertainty.

To illustrate, the performance specifications for an instrumentation amplifier can include accuracy, zero, nonlinearity, noise, drift, common mode rejection, input bias current, and the effect of temperature on both gain and offset. All are considered independent of each other. To estimate overall or total performance, these various performance specifications or errors must be statistically combined. In addition, the effects of temperature on both gain and offset are specified as a temperature coefficient and can be quantified for a specific application by using an allowance for the change in temperature. The methodology for combining elemental errors is to convert each specification into a standard uncertainty (Ref. 5). This requires that both the frequency distribution and confidence interval be known so that each specification can be adjusted to achieve a standard uncertainty. If the frequency distribution is not known, a reasonable default approach is to use a rectangular or equal probability distribution (Ref. 3).

The various standard uncertainties are combined using the RSS method to establish the combined standard measurement uncertainty (Ref. 3). When using manufacturers' specifications, it is assumed that they are all independent. An additional assumption is that the measurement performance is modeled by a normal distribution. The expanded uncertainty or total uncertainty is determined by multiplying the standard uncertainty with a coverage factor such as 2 or 3 (Ref. 3). A coverage factor of 2 defines the interval that will contain 95%, and 3 would be used to define the 99.7% interval.

2.5 THE METHODOLOGY SUMMARIZED

The recommended design methodology consists of the following:

1. Sketching a block diagram of the system by identifying the various equipment that forms the system, identifying the signal voltages, and identifying the methodology that will be used to achieve traceability of the measurements to national standards

- 2. Using manufacturer specifications to identify all relevant performance attributes and list each under the appropriate system equipment
- 3. Identifying those equipment specifications which are affected by the environment and computing the effects of each based on an understanding of the operating environment. For measurement systems, temperature is the dominant environmental factor affecting both gain and offset.
- 4. Converting each specified parameter or system attribute into a standard uncertainty in consistent units such as % FS or volts
- 5. Combining the different standard uncertainties using the RSS technique. Note that all of the specifications must be in consistent units such as V or % FS before they are combined. Note that in some engineering applications, it is necessary to separate the elemental errors into systematic and random error categories and to combine these using RSS.
- 6. Applying a coverage factor of 2 to the combined standard uncertainty to establish U₉₅.

3.0 RESULTS

3.1 GENERAL PURPOSE VOLTAGE MEASUREMENTS

Figure 1 illustrates a simple functional block diagram of the proposed system for measuring analog parameters. As shown, the system includes an Agilent reference meter which is used to provide traceability to national standards. The system consists of an instrumentation amplifier per channel followed by a shared multiplexer/analog-digital-converter which is interfaced to a computer. To accommodate a wide range of measurements, the input amplifiers have differential inputs and operate from ±5mV to ±10V FS. The requirement as listed previously is ±0.04% FS, 95% Confidence, ±10mV FS.

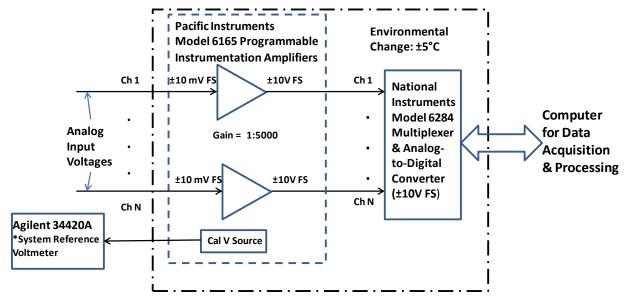


Figure 1. System Block Diagram

3.1.1 PACIFIC MODEL 6100/6165 PROGRAMMABLE INSTRUMENTATION AMPLIFIERS

The manufacturer's specifications listed below were confirmed with the manufacturer to represent 99.7% confidence and are assumed to be normally distributed. While not stated in the specification, specifications listed as % are assumed to be % FS. The specifications are included in the Appendix. Each specification is listed below and summarized in Table 2.

Gain Accuracy: There are 16 different fixed gain steps with an accuracy of ±0.05%FS. This represents a systematic error that can be reduced by computing the actual gain using a known voltage measured by the system reference voltmeter, Agilent 34420A.

Gain Stability, Time: ±0.02% FS for 30 days. Since the system is periodically calibrated in place, this error can be effectively mitigated.

Gain Stability, Temperature: $\pm 0.005\%$ /°C. Since the equipment can be exposed to a temperature variation of ± 5 °C, the thermal stability is the product of these two numbers or $\pm 0.025\%$ FS. This is a random error that is assumed to have a triangular distribution.

Linearity: ±0.01%FS for gains < 1,000 and ±0.02%FS for gains >1,000. Linearity is assumed to be a fixed error at any specific input and is normally distributed.

Common Mode Rejection Ratio: 60 dB plus gain in dB up to 120 dB for balanced input. Assuming a balanced input and using a gain of 1,000, the common mode is 120 dB. Assuming a common mode of $\pm 5V$, the common mode error is $\pm 5~\mu V$ or $\pm 0.00005\%$ FS. For strain-gauge transducers where the common mode voltage is ½ the excitation voltage, this is a systematic error that can be effectively eliminated.

Zero: Automatic zero to $\pm 2~\mu V$ RTI (relative to input) or $\pm 1.0~mV$ RTO (relative to output). On a gain of 1,000, this is $\pm 2.0~mV$ or $\pm 0.02\%$ FS and is a systematic error.

Zero Stability, Time: $\pm 5~\mu V$ RTI, $\pm 1.0~m V$ RTO. On a gain of 1,000, this is $\pm 6~m V$ or $\pm 0.06\%$ FS. However, since the manufacturer's specification is for 1-year stability, this is not indicative of how the system will be operated. Typically, offset and span corrections are performed prior to testing. Accordingly, a 24-hr specification obtained from the manufacturer ($\pm 2~\mu V$ RTI $\pm 0.4~m V$ RTO) applies. On a gain of 1,000, this error is $\pm 2.4~m V$ or $\pm 0.024\%$ FS. This is a random error assumed to be normally distributed.

Zero Stability, Temperature: $\pm 1~\mu V$ RTI, $\pm 0.2~mV$ RTO/°C. On a gain of 1,000 and for a ± 5 °C change, this is 1.0 mV, $\pm 1.0~mV$ or $\pm 2~mV$ or $\pm 0.02\%$ FS. This is a random error with an assumed triangular distribution.

Source Current, Time: ± 25 nA. Assuming a source impedance of 300 Ω , this produces an error at the amplifier output of $\pm 0.075\%$ FS. This is considered a systematic error.

Source Current, Temperature: ± 0.05 nA/°C. Assuming a ± 5 °C change and a gain of 1,000, the error at the amplifier output is ± 0.000025 V or ± 0.00025 % FS.

Noise (10 kHz): $2.0~\mu\text{V}$ RTI plus 0.3~mV RTO, RMS. On a gain of 1,000, this is 2.3~mV or 0.023% FS rms or 0.032% FS peak. This is a random error with an assumed triangular distribution.

In Table 2, the mitigated uncertainty represents the most probable estimate of uncertainty assuming the following:

- 1. Gain and zero uncertainties are mitigated to the uncertainty of the Agilent 34420A.
- 2. The system is routinely rezeroed during operations, so a 24-hr zero stability term is more appropriate.
- 3. The common mode voltage error for strain-gauge inputs is zeroed out as part of the operational procedures.

Table 2. Summary for Pacific Instruments Model 6100/6165

PARAMETER	SPECIFICATION, ±3σ	DISTRIBUTION	STANDARD UNCERTAINTY	MITIGATED UNCERTAINTY
Gain Accuracy, G = 1,000	±0.05% FS	Normal	±0.017% FS	±0.0018% FS, FS = 10 mV. Using Agilent 34420A
Gain Stability, Time	±0.02% FS	Normal	±0.007% FS	0.0%FS. The fixed error is removed as part of operational checks
Gain Stability, 5°C Temperature	±0.025% FS	Triangular	±0.01% FS	
Linearity, G = 1,000	±0.02% FS	Normal	±0.007% FS	
Common Mode (5V)	120 dB	Normal	±0.00002% FS	±0.0% FS. The fixed error is zeroed out for bridge inputs
Zero	±0.02% FS	Normal	±0.007% FS	±0.0018% FS. Using Agilent 34420A
Zero Stability	±0.024% FS	Normal	±0.06% FS	±0.008% FS. Using a 24-hr spec
Zero Stability, 5°C Temperature	±0.02% FS	Triangular	±0.008% FS	
Source Current-300 Ω, Time	±25 nA	Normal	±0.025% FS	±0.0% FS for balanced bridge inputs
Source Current-300 Ω, 5°C Temperature	±0.05nA/°C	Triangular	±0.00025% FS	
Noise (10 KHz)	±0.023%FS rms	Triangular	±0.009% FS	

Standard Uncertainty		±0.07% FS	±0.02% FS
Expanded Uncertainty, 95% Confidence		±0.14% FS	±0.04% FS

3.1.2 NATIONAL INSTRUMENTS PXI-628X MULTIPLEXER/ADC

Common Mode Rejection Ratio, CMRR: 110 dB, Assumed Negligible

Crosstalk, Adjacent Channels, 10 VΔ: -75 dB, ±0.017% FS

Absolute Accuracy: ±0.01 FS, 99.7%

Table 3. Summary for National Instruments Model PXI-628X

PARAMETER	SPECIFICATION, ±3σ	DISTRIBUTION	STANDARD UNCERTAINTY	MITIGATED UNCERTAINTY
Common Mode Rejection Ratio	110 dB		Not a factor because of configuration	
Crosstalk, Adjacent Channels (Δ10V)	-75 dB	Normal	±0.017% FS	±0.00017% FS (using Δ of 0.1V)
Absolute Accuracy	980 μV		±0.01% FS	
Standard Uncertainty			±0.02% FS	±0.01% FS
Expanded Uncertainty, 95% Confidence			±0.04% FS	±0.02% FS

The adjacent channel crosstalk specified as -75 dB could be a significant error source. The worst case would be a 20-V difference between two adjacent channels. If so, this would become a 0.35% FS error and would dominate the other error sources. While a 20-V swing seems excessive, a 1-V difference between channels is plausible. In this case, the error would be 10 times that indicated in the above table.

3.1.3 Predicted Measurement Uncertainty for General Purpose Voltage Measurement Channels, 10mV Full Scale

The predicted performance is the combined uncertainties of the Pacific Model 6165 amplifier and the NI multiplexer/ADC and is indicated in Table 4. The computed uncertainty is $U_{95} = \pm 0.146\%$ FS. This exceeds the requirement of $U_{95} = \pm 0.04\%$ FS for the 10mV range. As shown in Tables 2 and 3, there are several methods to mitigate the uncertainty. If all mitigations are implemented, the resultant uncertainty would be $U_{95} = \pm 0.044\%$ FS, which when rounded is considered to meet the requirement of $U_{95} = \pm 0.04\%$ FS.

Table 4. Summary of Standard Uncertainties for General Purpose Voltage Inputs

Equipment Used for General	STANDARD	MITIGATED STANDARD
Purpose Voltage Measurements	UNCERTAINTY, U _c	UNCERTAINTY, U _c
Pacific Instruments Model 6165	±0.07% FS	±0.02% FS
National Instruments PXI-628X	±0.02% FS	±0.01% FS
MULTIPLEXER/ADC		
Combined Standard Uncertainty	±0.07% FS	±0.022% FS
Expanded Uncertainty, 95%	±0.14% FS	±0.044% FS

3.2 FORCE BALANCE MEASUREMENT DATA ACQUISITION SYSTEM

Figure 2 illustrates a simple functional block diagram of the system for measuring force balances and includes an Agilent reference meter which is used to provide traceability to national standards. As shown, the Pacific Model 6160 provides excitation to the balance gauge and also conditions and amplifies the bridge output signal. A Pacific Model 6165 is used to measure the applied excitation voltage. Both amplifier outputs are input to the National Instruments (NI) multiplexer where they are digitized. The force balance requirement is stated for the ±10-mV FS range, which is considered the critical measurement range.

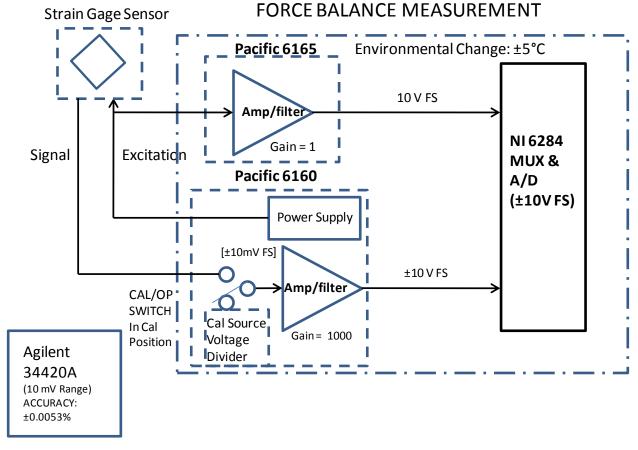


Figure 2. Block Diagram of Force Balance Measurement

3.2.1 Pacific Model 6100/6165 Programmable Instrumentation Amplifiers

This amplifier is used to measure the applied excitation voltage and will be operated on a gain of 1. The specifications are described in Section 3.1.1 and are repeated here only for those specifications that differ as a result of the gain being operated on a gain of 1 rather than a gain of 1,000.

Linearity: $\pm 0.01\%$ FS for gains < 1,000 and $\pm 0.02\%$ FS for gains >1,000. This is assumed to be a random error normally distributed.

Common Mode Rejection Ratio: 60 db plus gain in dB up to 120 dB for balanced input. Assuming a balanced input and using a gain of 1, the common mode is 60 dB. Assuming a common mode of 5V, the common mode error is ± 5 mV or $\pm 0.05\%$ FS. For strain-gauge transducers where the common mode voltage is $\frac{1}{2}$ the excitation voltage, this is a systematic error.

Zero: ±2 µV RTI or 0.3 mV RTO. On a gain of 1, this is 0.3 mV or 0.003% FS

Zero Stability, Time: $\pm 5~\mu V$ RTI, $\pm 1.0~mV$ RTO. On a gain of 1, this is $\pm 1~mV$ or $\pm 0.01\%$ FS. The manufacturer's specification is for 1-year stability and is not indicative of how the system will be operated. Typically, offset and span corrections are performed prior to testing. Accordingly, a 24-hr specification obtained from the manufacturer ($\pm 2~\mu V$ RTI $\pm 0.4~mV$ RTO) applies. On a gain of 1, this error is 0.4 mV or $\pm 0.004\%$ FS. This is a random error assumed to be normally distributed.

Zero Stability, Temperature: $\pm 1~\mu V$ RTI, $\pm 0.2 mV$ RTO/°C. On a gain of 1 and for a ± 5 °C change, this is $\pm 1.0~mV$ or $\pm 0.01\%$ FS. This is a random error with an assumed triangular distribution.

Source Current, Time: ± 25 nA. Assuming a source impedance of 300 Ω , this produces an error at the amplifier output of ± 25 E-06% FS. This is a systematic error.

Source Current, Temperature: ± 0.05 nA/°C. Assuming a ± 5 °C change and a gain of 1, the error at the amplifier output is $\pm 25E-06\%$ FS. This is a systematic error.

Noise (10 kHz): $2.0 \mu V$ RTI plus 0.3 mV RTO, RMS. On a gain of 1, this is 0.3 mV or 0.003% FS rms or 0.004%FS peak.

In Table 5, the mitigated uncertainty represents the most probable estimate of uncertainty assuming that (1) gain and zero uncertainties are mitigated to the uncertainty of the Agilent 34420A, (2) the system is routinely rezeroed during operations so a 24-hr zero stability term is more appropriate, and (3) the common mode voltage error for strain-gauge inputs is zeroed out as part of the operational procedure.

Table 5. Summary for Pacific Instruments Model 6100/6165

PARAMETER	SPECIFICATION, ±3σ	DISTRIBUTION	STANDARD UNCERTAINTY	MITIGATED UNCERTAINTY
Gain Accuracy, G=1	±0.05% FS	Normal	±0.017% FS	±0.0011% FS, FS=10V
Gain Stability, Time	±0.02% FS	Normal	±0.007% FS	±0.0% FS. Calibrated out
Gain Stability, 5°C Temperature	±0.025% FS	Triangular	±0.01% FS	
Linearity G=1	±0.01% FS	Normal	±0.003% FS	
Common Mode (5V)	60 dB	Normal	±0.017% FS	±0.0% FS. Zeroed out.
Zero	±0.003% FS	Normal	±0.001% FS	
Zero Stability, 24 hour	±0.004% FS	Normal	±0.001% FS	
Zero Stability, 5°C Temperature	±0.01% FS	Triangular	±0.003% FS	
Source Current-300Ω, Time	±25 nA	Normal	±75E-06% FS	
Source Current-300Ω, 5°C Temperature	±0.05 nA/°C	Triangular	±8E-08% FS	
Noise (10KHz)	±0.004% FS rms	Triangular	±0.002% FS	
Standard Uncertainty			±0.027% FS	±0.011% FS
Expanded Uncertainty, 95% Confidence			±0.055% FS	±0.022% FS

3.2.2 Pacific Model 6100/6160 Programmable Transducer Amplifier

The Model 6160 Programmable Transducer Amplifier is used to interface directly with the straingauge balance. The instrument is used to provide excitation voltage or current and is used to condition the balance gauge analog output voltage. The unit is typically operated on either a 5-or 10-mV/FS. For this analysis, the gain is 1,000.

Gain Accuracy: There are 16 different fixed gain steps with an accuracy of ±0.05%FS. This represents a systematic error that can be reduced by computing the actual gain using a known voltage measured by the system reference voltmeter, Agilent 34420A.

Gain Stability, Time: ±0.02% FS for 30 days. Since the system is periodically calibrated in place with zero set, the error is effectively mitigated

Gain Stability, Temperature: ±0.005%/°C. Since the equipment can be exposed to a temperature variation of ±5°C, the stability is the product of these two numbers ±0.025% FS. This is a random error that is assumed to be represented by a triangular distribution.

Linearity: $\pm 0.01\%$ FS for gains < 1,000 and $\pm 0.02\%$ FS for gains >1,000. This is a random error assumed to be normally distributed.

Common Mode Rejection Ratio: 60 db plus gain in dB up to 120 dB for balanced input. Assuming a balanced input and using a gain of 1,000, the common mode is 120 dB. Assuming a common mode of 5 V, the common mode error is 5 μ V or 0.00005% FS

Zero: $\pm 2~\mu V$ RTI or 0.3 mV RTO. On a gain of 1,000, this is 2.0 mV or 0.02% FS and is a systematic error.

Zero Stability, Time: $\pm 5~\mu V$ RTI, $\pm 1.0~m V$ RTO. On a gain of 1,000, this is $\pm 6~m V$ or $\pm 0.06\%$ FS. The manufacturer's specification is for 1-year stability and is not indicative of how the system will be operated. Typically, offset and span corrections are performed prior to testing. Accordingly, a 24-hr specification obtained from the manufacturer ($\pm 2~\mu V$ RTI $\pm 0.4~m V$ RTO) applies. On a gain of 1,000, this error is $\pm 2.4~m V$ or $\pm 0.024\%$ FS. This is a random error assumed to be normally distributed.

Zero Stability, Temperature: $\pm 1~\mu V$ RTI, $\pm 0.2~mV$ RTO/°C. On a gain of 1,000 and for a ± 5 °C change, this is 1.0 mV, $\pm 1.0~mV$ or $\pm 2~mV$ or $\pm 0.02\%$ FS. This is a random error with an assumed triangular distribution.

Source Current, Time: ± 25 nA. Assuming a source impedance of 350 Ω which is typical for strain-gauge balances at AEDC, this produces an error at the amplifier output of $\pm 0.088\%$ FS. This is a systematic error.

Source Current, Temperature: ±0.05 nA/°C. Assuming a ±5°C change and a gain of 1,000, the error at the amplifier output is ±0.0008% FS.

Noise (10 kHz): 2.0 μ V RTI plus 0.3 mV RTO, RMS. On a gain of 1,000, this is 2.3 mV or 0.023% FS rms or 0.032% FS peak.

In Table 6, the mitigated uncertainty represents the most probable estimate of uncertainty assuming that (1) gain and zero uncertainties are mitigated to the uncertainty of the Agilent 34420A, (2) the system is routinely rezeroed during operations so a 24-hr zero stability term is more appropriate, and (3) the common mode voltage error for strain-gauge inputs is zeroed out as part of the operational procedure.

Table 6. Summary for Pacific Instruments Model 6100/6160

PARAMETER	SPECIFICATION, ±3σ	DISTRIBUTION	STANDARD UNCERTAINTY	MITIGATED UNCERTAINTY
Gain Accuracy, G=1000	±0.05% FS	Normal	±0.017% FS	±0.0018% FS. Using Agilent 34420A
Gain Stability, Time	±0.02% FS	Normal	±0.007% FS	±0% FS. Calibrated out
Gain Stability, 5°C Temperature	±0.025% FS	Triangular	±0.01% FS	
Linearity, G=1000	±0.02% FS	Normal	±0.007% FS	
Common Mode (5V)	120 dB	Normal	±0.0002% FS	±0.0% FS. The fixed error is zeroed out for bridge inputs
Zero	±0.02% FS	Normal	±0.007% FS	±0.0018% FS. Using Agilent 34420A
Zero Stability	±0.024% FS	Normal	±0.06% FS	±0.008% FS. Using 24-hr stability
Zero Stability, 5°C Temperature	±0.02% FS	Triangular	±0.008% FS	
Source Current- 300Ω, Time	±25 nA	Normal	±0.025% FS	±0.0% FS for balanced bridge inputs
Source Current- 300Ω, 5°C Temperature	±0.05nA/°C	Triangular	±0.00025% FS	
Noise (10 KHz)	±0.023% FS rms	Triangular	±0.009% FS	
Standard Uncertainty			±0.07% FS	±0.02% FS
Expanded Uncertainty, 95% Confidence			±0.14% FS	±0.04% FS

3.2.3 National Instruments PXI-628X Multiplexer/ADC

Common Mode Rejection Ratio, CMRR: 110 dB, Assumed Negligible

Crosstalk, Adjacent Channels, 10VΔ: -75 dB, ±0.017% FS

Absolute Accuracy: ±0.01 FS, 99.7%

The errors for the National Instruments Multiplexer/ADC are summarized in Table 7.

Table 7. Summary for National Instruments PXI-628X Multiplexer/ADC

PARAMETER	SPECIFICATION, ±3σ	DISTRIBUTION	STANDARD UNCERTAINTY	MITIGATED UNCERTAINTY
Common Mode Rejection Ratio	110 dB		Not a factor because of configuration	
Crosstalk, Adjacent Channels (Δ10V)	-75 dB	Normal	±0.017% FS	±0.00017% FS
Absolute Accuracy	980 μV		±0.01% FS	
Standard Uncertainty			±.02% FS	±0.01% FS
Expanded Uncertainty, 95% Confidence			±0.04% FS	±0.02% FS

3.2.4 Predicted Measurement Uncertainty for Force Balance

The predicted performance is the combined uncertainties of the Pacific Model 6165 instrumentation amplifier (used to measure the excitation voltage), the Pacific Model 6160 Programmable Transducer Amplifier (used to measure the force balance output signal), and the NI multiplexer/ADC. Table 8 summarizes the standard uncertainties for the various equipment used to measure force balance inputs. Using the mitigations identified previously, the projected uncertainty for the force balance channels is $U_{95} = \pm 0.052\%$ FS, which when rounded meets the requirement of $U_{95} = \pm 0.05\%$ FS.

Table 8. Summary of Standard Uncertainties for Force Balance Inputs

FORCE BALANCE EQUIPMENT	STANDARD	MITIGATED
	UNCERTAINTY, U _c	UNCERTAINTY, U _c
Pacific Instruments Model 6165	±0.027% FS	±0.01% FS
National Instruments PXI-628X	±0.02% FS	±0.01% FS
MULTIPLEXER/ADC		
Pacific Instruments Model 6160	±0.07% FS	±0.02% FS
National Instruments PXI-628X	±0.02 FS	±0.01 FS
MULTIPLEXER/ADC		
Combined Standard Uncertainty	±0.08% FS	±0.026% FS
Expanded Uncertainty, 95%	±0.16% FS	±0.052% FS

4.0 SUMMARY

Using the various equipment manufacturers' specifications, the measurement uncertainty has been predicted for both the general purpose voltage measurements and the force balance measurements. The analysis identified several significant error sources such as the gain accuracy specification of $\pm 0.05\%$ FS, zero of $\pm 0.02\%$ FS, and zero stability of $\pm 0.024\%$ FS that would prevent the requirements from being met without special action. By understanding the different errors, specific actions such as zero and gain calibrations were identified that enabled the system to meet the requirements.

The methodology described in this paper represents a way of using available information from equipment manufacturers and other sources to estimate or predict the uncertainty. As such, this is an estimate and should be replaced with end-to-end system evaluations.

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APPENDIX A. AGILENT TECHNOLOGIES



Agilent 34420A NanoVolt/Micro-Ohm Meter

Data Sheet



- 7½ digits resolution
- 100 pV, 100 $n\Omega$ sensitivity
- 1.3 nVrms, 8 nVpp noise performance
- Built-in low noise 2 channel
 scenner
- Direct SPRT, RTD, Thermistor, and Thermocouple measurements

Nanovolt Performance at a Microvolt Price

The Agilent Technologies 34420A nano-Volt/micro-Ohm meter is a high-sensitivity multimeter optimized for performing low-level measurements. It combines low-noise voltage measurements with resistance and temperature functions, setting a new standard in low-level flexibility and performance.

Take the Uncertainty Out of Your Low-Level Measurements

Low-noise input amplifiers and a highly tuned input protection scheme bring reading noise down to 8 nVpp. Combine this with 7½ digits of resolution, selectable analog and digital filtering, 2 ppm basic 24-hour dcV accuracy, and a shielded, copper pin connector and you've got accurate, repeatable measurements you can count on.

Two Input Channels

An integral two-channel programmable scanner simplifies voltage comparisons. Built-in ratio and difference functions enable automated two channel measurements without the need for an external nanoVolt scanner. Both channels share the same low noise specifications to ensure accurate comparisons.

Built-In Resistance and Temperature

The 34420A combines its low-noise nano-Volt input circuits with a high-stability current source to provide precise low-level resistance measurements – no more hassling with the cost and complexity of an external current source. Three resistance modes are included:

- Standard
- · Low-power
- Voltage-limited for dry-circuit testing

Offset compensation is also provided to minimize thermal EMFs and associated errors.

SPRT Measurements

Built-in ITS-90 conversion routines accept the calibration coefficients from your SPRT probe for direct temperature measurement and conversion. Thermocouples, thermistors, and RTDs are also supported.

Unequaled Versatility

The 34420A gives you the versatility to tackle your most challenging tasks, both on the benchtop and in your automated system. Standard features include RS-232 and GPIB interfaces, SCPI and Keithley 181 programming language, 1024-reading memory, scaling and statistics, and a chart recorder analog output.

Agilent IntuiLink: Easy Data Access

The included Agilent IntuiLink software allows your captured data to be put to work easily, using PC applications such as Microsoft Excel® or Word® to analyze, interpret, display, print, and document the data you get from the 34420A. You can specify the meter setup and take a single reading or log data to the Excel spreadsheet in specified time intervals. To find out more about IntuiLink visit www.agilent.com/find/intuilink

Quality You Can Count On

The 34420A gives you the quality and reliability you expect from Agilent Technologies. From the product's proven >150,000 hour Mean Time Between Failure, to its standard 1-year warranty, Agilent stands behind you to bring a new level of confidence to your low-level measurements.



Specifications

Accuracy Specifications \pm (% of reading + % of range) ¹

Function	Range ²	Test Current	24 Hour 23 °C ± 1 °C	90 Day 23 °C ± 5 °C	1 Year 23 °C ± 5 °C	Temperature Coefficient 0 °C—18 °C 28 °C—55 °C	Maximum per Lead Resistance
dc Voltage	1.0000000 mV ³ 10.000000 mV ³ 100.00000 mV 1.0000000 V 10.000000 V 100.00000 V ⁴		0.0025 + .0020 0.0025 + .0002 0.0015 + .0003 0.0010 + .0003 0.0002 + .0001 0.0010 + .0004	0.0040 + .0020 0.0040 + .0002 0.0030 + .0004 0.0025 + .0004 0.0020 + .0004 0.0025 + .0005	0.0050 + .0020 0.0050 + .0003 0.0040 + .0004 0.0035 + .0004 0.0030 + .0004 0.0035 + .0005	0.0004 + .0001 0.0004 + .0001 0.0004 + .00006 0.0004 + .00004 0.0001 + .00002 0.0004 + .00005	
Resistance §	1.0000000 Ω 10.000000 Ω 100.00000 Ω 1.000000 ΚΩ 10.00000 ΚΩ 100.00000 ΚΩ 1.000000 ΜΩ	10 mA 10 mA 10 mA 1 mA 1 mA 100 μA 10 μA 5 μA	0.0015 + .0002 0.0015 + .0002 0.0015 + .0002 0.0015 + .0002 0.0015 + .0002 0.0015 + .0002 0.0015 + .0003 0.0020 + .0003	0.0050 + .0002 0.0040 + .0002 0.0040 + .0002 0.0040 + .0002 0.0040 + .0002 0.0040 + .0004 0.0050 + .0004	0.0070 + .0002 0.0060 + .0002 0.0060 + .0002 0.0060 + .0002 0.0060 + .0002 0.0060 + .0004 0.0070 + .0004	0.0005 + .00002 0.0005 + .00001 0.0005 + .00001 0.0005 + .00001 0.0005 + .00001 0.0005 + .00002 0.0006 + .00003	1 Ω 1 Ω 10 Ω 100 Ω 1 KΩ 1 KΩ 1 KΩ
Low Power Resistance ⁵	1.0000000 Ω 10.000000 Ω 100.00000 Ω 1.000000 ΚΩ 10.00000 ΚΩ 100.00000 ΚΩ 1.000000 ΜΩ	10 mA 10 mA 1 mA 100 μA 10 μA 5 μA 5 μA	0.0015 + .0002 0.0015 + .0002 0.0015 + .0002 0.0015 + .0002 0.0015 + .0004 0.0015 + .0012 0.0020 + .0003	0.0050 + .0002 0.0040 + .0002 0.0040 + .0002 0.0040 + .0002 0.0040 + .0004 0.0040 + .0015 0.0050 + .0004	0.0070 + .0002 0.0060 + .0002 0.0060 + .0002 0.0060 + .0002 0.0060 + .0004 0.0060 + .0015 0.0070 + .0004	0.0005 + .00002 0.0005 + .00001 0.0005 + .00001 0.0005 + .00001 0.0005 + .00001 0.0005 + .00003 0.0006 + .00003	1 Ω 1 Ω 10 Ω 100 Ω 1 ΚΩ 1 ΚΩ 1 ΚΩ
Voltage Limited Resistance 5,6	10.000000 Ω 100.00000 Ω	1 mA 100 μA	0.0020 + .0002 0.0025 + .0002	0.0050 + .0002 0.0050 + .0002	0.0070 + .0002 0.0070 + .0002	0.0005 + .00002 0.0005 + .00002	1 Ω 5 Ω

Channel 1 / Channel 2 (dcV Ratio) Channel 1-Channel 2 (dcV Difference)

Ratio Error in % = Channel 1 accuracy in % + Channel 2 accuracy in % Difference Error = Channel 1 (% of reading + % of range) + Channel 2 (% of reading + % of range)

Temperature (resolution = 0.001 °C)

SPRT 7 SPRT Probe Accuracy + 0.003°C RTD Probe Accuracy + 0.05°C
Thermistor Probe Accuracy + 0.1°C Thermistor Thermocouple 8 Thermocouple Probe Accuracy + 0.2°C

DC Voltage Noise 9

	Observation Period									
Range	2-Minute RMS Noise	2-Minute Peak-Peak Noise	24-Hour Peak-Peak Noise							
1 mV	1.3 nVrms	8 nVpp	12 nVpp							
10 mV	1.5 nVrms	10 nVpp	14 nVpp							
100 mV	10 nVrms	65 nVpp	80 nVpp							
1 V	100 nVrms	650 nVpp	800 nVpp							
10 V	450 nVrms	3 µ√рр	3.7 µVpp							
100 V	11 μVrms	75 µVpp	90 µVpp							

DC Voltage Noise vs Source Resistance 10

Source Resistance	Noise	Analog Filter	Digital Filter	
0 Ω	1.3 nVrms	Off	Med	
100 Ω	1.7 nVrms	Off	Med	
1k Ω	4 nVrms	Off	Med	
10k Ω	13 nVrms	Off	Med	
100k Ω	41 nVrms	On	Med	
1Μ Ω	90 nVrms	On	Slow	

- Specifications are for Channel 1 or Channel 2, after 2-hour warm-up, resolution at 7.5 digits (100 NPLC), with FILTERS off. RESISTANCE specifications are for 4-wire Ohms or 2-wire ohms using Null. Without Null, add 0.2 Ohms additional error in 2-wire Ohms function. For Analog Filter ON, add 0.002% of reading.

 2 20% overrange on all ranges except 5% on Voltage Limited Resistance.

 3 After using Math Null. If Null is not used add 100 nanoVolts.

 4 Channel 1 only.

 5 Channel 1 only. Resistance measurements, for NPLC <1, add 160 μΩ rms noise.

 6 Voltage limit can be set to 20 mV (default) 100 mV, or 500 mV. Measured.

- noise. 6 Voltage limit can be set to 20 mV (default), 100 mV, or 500 mV. Measured resistance plus Channel 1 HI and LD lead resistance is limited to 10.5 Ω on the 10 Ω range and 105 Ω or the 100 Ω range. 7 For 25 Ω SPRT with triple-point of water check within the last 4 hours.
- 7 For 25 0 SPRT with triple-point of water check within the last 4 hours. Without the triple-point of water check, add 0.013°C for 24 hours, add 0.035°C for 90 day, and add 0.055°C for 1 year specifications.
 8 For fixed reference junction. Add 0.30C for external reference junction, add 2.00C for internal reference junction.
 9 After a 2-hour warm-up, ± 10C, 65 digits (10 PLC) with Analog Filter Off and Digital Filter Medium (50 reading average).
 2-minute rms and 24-hour noise typical. For measurements using 0.02 or 0.2 NPIC. add 300 nV rms noise.
 10 Typical noise behavior for Ch 1 or Ch 2, after 2 hour warm-up, 6.5 digits (10

- THE C. and OUT IN THIS HOUSE.

 10 Typical noise behavior for Ch 1 or Ch 2, after 2 hour warm-up, 6.5 digits (10 PLC), 2 minute observation period on 1 mV range. For peak-to-peak noise, multiply rms noise by 6.

2

Measurement Characteristics

DC Voltage Measurement Method: Continuously integrating multi-slope III A-D Converter A-D Linearity: 0.00008% of reading + 0.00005% of range Input Resistance 100V (Ch1 only): 10 MΩ +- 1% 1mV through 10V: > 10 G Ω , in parallel with < 3.6 nF Input Bias Current: <50 nA at 25 °C Injected Current: <50 nA pp at 50 or 60 Hz Input Protection: 150 V peak any input terminal to Channel 1 LO, continuous Channel-to-channel switching error (typical): 3 nV

Channel Isolation

Isolation between input channels >10¹⁰ Ω

350 V peak any input terminal to earth. Impedance from any input terminal to earth is >10 G Ω and <400 pF

Maximum Voltage:

Channel 1 LO to Channel 2 LO, 150V peak

Resistance

Measurement Method:

Selectable 4-wire or 2-wire ohms. Current Source referenced to Channel 1 LO input

Offset Compensation:

Used on all ranges except 100 k Ω and 1 M $\Omega.$ Can be turned off if desired

Protection: 150 V peak

Open Circuit Voltage:

For Resistance and Low Power Resistance <14 V. 20 mV, 100 mV, 500 mV selectable clamp

Temperature

SPRT:

ITS-90 calibrated temperature with the range of -190°C to +660°C

Thermocouple:

ITS-90 conversions of Type B, E, J, K, N, R, S, T

Thermistor: 5 kΩ

RTD: Type α =.00385 and α =.00392. $R_{\rm o}$ from $4.9~\Omega$ to $2.1~k\Omega.$ ITS -90 (IEC-751) Callendar Van Dusen conversion

Measurement Noise Rejection 60 (50) Hz

dc CMRR: 140 dB

ac CMRR: 70 dB

Integration Time	Normal Mode Rejection ²	
200 plc/3.335 s (4 s)	110 dB ³	
100 plc/1.675 s (2 s)	105 dB ³	
20 plc/334 ms (400 ms)	100 dB ³	
10 plc/167 ms (200 ms)	95 dB3	
2 plc/33.3 ms (40 ms)	90 dB	
1 plc/16.7 ms (20 ms)	60 dB	
<1 plc	0	

Operating Characteristics

Function	Digits	Integration Time	Readings/s 5
dcV	71/2	200 plc	.15 (.125)
Thermocouple	71/2	100 plc	.3 (.25)
10.0	61/2	20 plc	1.5 (1.25)
	61/2	10 plc	3 (2.5)
	51/2	1 plc	25 (20.8)
	51/2	0.2 plc	100 (100)
	41/2	0.02 plc	250 (250)
Resistance	71/2	200 plc	.075 (.062)
dcV1/DCV2	71/2	100 plc	.15 (.125)
dcV 1-2	61/2	20 plc	.75 (.625)
RTD	61/2	10 plc	1.5 (1.25)
Thermistor	51/2	1 plc	12.5 (10.4)
0.2 plc	50 (50)	3.0. #A00000	on an exercise Colombia A
25	41/2		
0.02 plc	125 (125)		

System Speeds

Configuration Rates: 26/s to 50/s Autorange Rate (Volts): >30/s ASCII reading to RS-232: 55/s ASCII reading to GPIB: 250/s Max. Internal Trigger Rate: 250/s Max. Ext. Trig. Rate to Memory: 250/s

Triggering and Memory

Memory: 1024 readings

Reading HOLD Sensitivity: 10%, 1%, 0.1%, or 0.01% of range Samples/Trigger: 1 to 50,000 Trigger Delay: 0 to 3600 s; 10 µs step size External Trigger Delay: <1 ms External Trigger Jitter: <500 µs

Math Functions

NULL (Channel 1 dcV, Channel 2 dcV, Difference, Resistance, Temperature)

STATS (Min, Max, Average, Peak-Peak, Standard Deviation, Number of readings)

SCALE (Allows linear scaling as y = mx+b)

CHART NULL (Establishes zero for rear panel

Filter (Analog or Digital or Both)

Analog:

Low pass 2 pole @ 13Hz, available for dcV 1 mV, 10 mV, 100 mV range

Digital:

Moving average filter, 10 (fast), 50 (medium), or 100 (slow) reading averages.

- For 1 k Ω unbalanced in LO lead. For power line frequency \pm 0.1%, Filters OFF. For Digital Filter slow add 20 db, for medium or fast add 10 db for NPLC ³ 1. For power line frequency ± - 1%, use 80 db,
- for + 3% use 60 db
- Speeds are for delay 0, Display OFF, Filters OFF, Offset Compensation OFF.
- Reading speeds for 60 Hz or (50 Hz), 100 mV through 100 V ranges. 1 mV range 30/s MAX, 10 mV range 170/s MAX, thermocouple 120/s MAX. Speeds are for NPLC 0.02, Delay 0, Display 0FF,
- Chart Out OFF.

Chart Out (Analog Out)

Maximum output: ± 3V Resolution: 16 bits

Accuracy: ± 0.1% of output + 1 mV Output Resistance: 1 kΩ ± 5%

Update rate: once per reading

Span and Offset: Adjustable

Standard Programming Languages SCPI (IEEE 488.2), Keithley 181

Accessories Included

4 ft low thermal cable with copper spade lugs, Kelvin clip set, 4-wire shorting plug, user's manual, service manual, test report, contact cleaner, and power cord.

General Specifications

Front Panel Connection

Shielded, low thermal, 99% copper contacts.

Power Supply:

100V/120V/220V(230V)/240V +- 10%.

Power Line Frequency

45 Hz to 66 Hz and 360 Hz to 440 Hz. Automatically sensed at power-on.

Power Consumption:

25VA peak (10W average).

Operating Environment:

Full accuracy for 0 °C to 55 °C. Full accuracy to 80% R.H. up to 30 °C.

Storage Environment -40 °C to 75 °C.

Size: 254.4 mm W x 374.0 mm L x 103.6 mm H

(10.02" W x 14.72" L x 4.08" H)

Weight: 3 kg (6.5 lbs)

Designed to CSA, UL-1244, IEC-1010. RFI and ESD: CISPR 11.

3



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LXI is the LAN-based successor to GPIB, providing faster, more efficient connectivity. Agilent is a founding member of the LXI consortium.

Remove all doubt

Our repair and calibration services will get your equipment back to you, performing like new, when promised. You will get full value out of your Agilent equipment throughout its lifetime. Your equipment will be serviced by Agilent-trained technicians using the latest factory calibration procedures, automated repair diagnostics and genuine parts. You will always have the utmost confidence in your measurements.

Agilent offers a wide range of additional expert test and measurement services for your equipment, including initial start-up assistance onsite education and training, as well as design, system integration, and project management.

For more information on repair and calibration services, go to:

www.agilent.com/find/removealldoubt

Ordering Information

34420A nanoVolt/micro-Ohm meter

Includes low-thermal input cable (34102A), low-thermal shorting plug (34103A), Kelvin clip set (11062A), operating manual, service manual, and quick reference guide, test report with calibration sticker, 2.3 ml bottle of contact cleaner, and power cord.

34420A-1CM Rack mount kit (P/N 5062-3972) 34420A-ABA English localization 34420A-ABD German localization: translated operating manual 34420A-ABF French localization: translated operating manual 34420A-ABJ Japanese localization: translated operating manual 34420A-A6J ANSI Z540 compliant

calibration

Accessories

34102A Low-thermal input cable (fourconductor) with copper spade lugs 34103A Low-thermal shorting plug 34104A Low-thermal input connector 34161A Accessory pouch

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APPENDIX B. NATIONAL INSTRUMENTS



Technical Sales United States (866) 531-6285 info@ni.com

Requirements and Compatibility | Ordering Information | Detailed Specifications | Pinouts/Front Panel Connections

Last Revised: 2011-10-21 10:31:23.0

High-Accuracy M Series Multifunction DAQ - 18-Bit, up to 625 kS/s, up to 32 Analog Inputs



- 16 or 32 analog inputs at 18 bits, 625 kS/s (500 kS/s scanning)
- Up to 4 analog outputs at 16 bits, 2.8 MS/s (3 µs full-scale settling)
- 7 programmable input ranges (±100 mV to ±10 V) per channel
- · Programmable, onboard lowpass filtering



- Up to 48 TTL/CMOS digital I/O lines (up to 32 hardware-timed at 10 MHz)
- Two 32-bit, 80 MHz counter/timers
- · Analog and digital triggering
- NI-MCal calibration technology for improved measurement accuracy

Overview

NI M Series high-accuracy multifunction data acquisition (DAQ) devices are optimized for 18-bit analog input accuracy. This resolution is equivalent to 5½ digits for DC measurements. To ensure accuracy, the NI-PGIA 2 amplifier technology is optimized for low noise and fast settling to 18 bits, and the onboard lowpass filter rejects high-frequency noise and prevents aliasing. M Series devices are ideal for applications including test, including test, and III high-accuracy devices have a minimum of 16 analog inputs, 24 digital I/O lines, seven programmable input ranges, analog and digital triggering, and two counter/timers. They also have an extended two-year calibration interval.

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Requirements and Compatibility

OS Information

- Windows 2000/XP
- Windows Vista x64/x86
- Linux®
- Mac OS X
- Windows 7

Driver Information

- NI-DAQmx
- NI-DAQmx Base

Software Compatibility

- ANSI C
- LabVIEW
- LabWindows/CVI
- Measurement Studio Professional Edition
- Visual Basic
- Visual Studio .NET

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Comparison Tables

Joinpu	Oniparison rables								
Family	Bus	Analog Inputs	Al Resolution (Bits)	Analog Outputs	AO Resolution (Bits)	Max A O Update Rate (MS/s)	A O Range	Digital I/O	Correlated (clocked) DIO
NI 6280	PCI, PXI	16	18	×	(8)	8	*	24	8, up to 10 MHz
NI 6281	PCI, PXI	16	18	2	16	2.8	Programmable per channel	24	8, up to 10 MHz
NI 6284	PCI, PXI	32	18	58	858	8	8	48	32, up to 10 MHz

Family	Bus	Analog Inputs	Al Resolution (Bits)	Analog Outputs	AO Resolution (Bits)	Max A O Update Rate (MS/s)	A O Range	Digital I/O	Correlated (clocked) DIO
NI 6289	PCI, PXI	32	18	4	16	2.8	Programmable per channel	48	32, up to 10 MHz

Application and Technology

M Series for Test

For test, you can use M Series high-accuracy analog inputs and 10 MHz digital lines with NI signal conditioning for applications including electronics test, component characterization, and sensor and signal measurements requiring instrument-class accuracy. The 18-bit hanalog to digital converter (ADC) and available filtering provide a 4 times increase in resolution and 5 times more measurement sensitivity. With fast sampling rates and a low noise floor, these devices can accurately acquired dynamic signals. For better noise rejection, the onboard lowpass filters significantly improve device accuracy. Advanced analog clamping circuitry protects the hardware from overvoltage conditions and ensures accurate measurements on nonsaturated channels. High-accuracy M Series devices are compatible with NI SCC and SCXI signal conditioning platforms, which provide amplification, filtering, and power for virtually every type of sensor. These platforms also are compilant with IEEE 1451.4 smart transducer electronic data sheet (TEDS) sensors, which offer digital storage for sensor data sheet information.

M Series for Control

M Series digital lines can drive 24 mA for relay and actuator control. By clocking the digital lines as fast as 10 MHz, you can use these lines for pulse-width modulation (PWM) to control valves, motors, fans, lamps, and pumps. With four waveform analog outputs, two 80 MHz counter/timers, and six DMA channels, M Series devices can execute multiple control loops simultaneously. The analog outputs on the high-accuracy M Series devices can generate up to 2.86 MS/s and provide user-defined programmable offsets and ranges for maximum waveform resolution over any custom range. High-accuracy M Series devices also have direct support for encoder measurements, protected digital lines, and digital debounce filters for control applications. With up to 32 analog inputs, 32 clocked digital lines, and four analog outputs, you can execute multiple control loops with a single device. For higher-count control loops, you can use M Series devices in conjunction and tightly synchronized with National Instruments analog output devices for 64 or more loops. With the NI SoftMotion Development Module for LabVIEW, you can create a complete custom motion controller with M Series devices.

M Series for Design

For design applications, you can use the wide range of I/O - from 32 analog inputs to 48 digital lines - to measure and verify prototype designs. M Series devices and NI LabVIEW SignalExpress interactive measurement software deliver benchtop measurements to the PC. With LabVIEW SignalExpress interactive configuration-based steps, you can quickly create design verification tests. The fast acquisition and generation rates of high-speed M Series devices along with LabVIEW SignalExpress provide on-the-fly design analysis. You can convert your tested and verified LabVIEW SignalExpress projects to LabVIEW applications for immediate M Series DAQ use and bridge the gap between test, control, and design applications.

Hybrid-Slot-Compatible PXI Modules

M Series modules for PXI are hybrid-slot-compatible so that you can use them in both PXI slots and the hybrid-slots found in new PXI Express chassis. The PXI Systems Alliance specifies that hybrid-slot-compatible PXI modules use modified slot connectors to mechanically fit in both PXI slots and hybrid slots. This mechanical change:

- · Provides compatibility with past, current, and future PXI chassis
- Maintains existing product specifications
- Requires no software changes (application or driver)
- Maintains speed and capability of all PXI communication (PXI Express signaling is not provided)

However, hybrid-slot-compatible PXI modules do not include the pins used to implement PXI local bus communication, which is used for backplane SCXI control from the right-most PXI slot in PXI/SCXI combination chassis (NI PXI-1010, PXI-1011, PXI-1050, and PXI-1052). For these applications, NI provides unmodified M Series PXI modules that maintain the required local bus capabilities. Refer to the SCXI Control of PXI/SCXI Combination Chassis section in the Ordering Information section for part numbers.

Simultaneous and Intelligent Data Acquisition

When you need to obtain performance from a data acquisition device beyond the capabilities of a multifunction DAQ device, National Instruments provides simultaneous sampling with the S Series and intelligent DAQ with the R Series. The S Series architecture dedicates an ADC per channel to provide higher aggregate sampling rates compared to multiplexed devices. S Series devices are ideal for applications including IF digitization, transient recording, ultrasound and sonartesting, and high-energy physics.

R Series multifunction DAQ devices contain a 1M/3M gate field-programmable gate array (FPGA) that is reconfigurable using the NI LabVIEW FPGA Module. These devices have up to eight independent 16-bit analog outputs with up to 200 kHz simultaneous sampling, up to eight independent 16-bit analog outputs with up to 1 MHz simultaneous update rates, and up to 96 digital I/O lines configurable at rates up to 40 MHz. You can customize these devices to develop capabilities such as complete control over the synchronization and timing of all signals and operations; user-defined onboard decision-making logic; and digital lines individually configurable as input, output, counter/timers, PVMM, flexible encoder inputs, or user-defined communication protocols.

Signal Conditioning

Signal conditioning is required for sensor measurements or voltage inputs greater than 10 V. NI SCXI is a versatile, high-performance signal conditioning platform, optimized for high-channel-count applications. NI SCC provides portable, flexible signal conditioning options on a per-channel basis. Visit ni.com/sigcon for resources on available NI signal conditioning.

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Ordering Information

For a complete list of accessories, visit the product page on ni.com.

Products	Part Recommended Accessories Number	Part Number
NI PCI-6280		

NI PCI-6280 Each NI PCI-6280 requires: 1 Cable, 1 Connector Block	779108-01 Cable: Shielded - SHC68-68-EPM Cable 192061 (2m) **Also available: Unshielded	1-02
	Connector Block: Screw Terminals - 776844 SCB-68 ***Also available: BMC Termination	4-01
II PXI-6280	Also available. Direct artification	
II PXI-6280 ach NI PXI-6280 requires: 1 Cable, 1 Connector Block	779120-01	1-02
	**Also avallable: Unshielded Connector Block: Screw Terminals- 776844	4 04
	Connector Block: Screw Terminals - 776844 SCB-68 ***Also available: BNC Termination	+01
II PCI-6281		
4 PCL-6281 Each NI PCL-6281 requires: 1 Cable, 1 Connector Block	779109-01 Cable: Shielded - SHC68-68-EPM Cable 192061 (2m) **Also available: Unshielded	1-02
	Connector Block: Screw Terminals - 776844 SCB-68	4-01
NI PXI-6281	**Also avallable: BNC Termination	
II PXI-6281	779121-01 Cable: Shielded - SHC68-68-EPM Cable: 192061	1-02
Each NI PXI-6281 requires: 1 Cable, 1 Connector Block	(2m) **Also available: Unshielded	
	Connector Block: Screw Terminals - 776844	4-01
	SCB-68 **Also available: BNC Termination	
# PCI-6284		
il PCI-6284 Each NI PCI-6284 requires: 2 Cables, 2 Connector Blocks	779110-01 Connector 0:	
actifyl FCI-0204 feytiles. 2 Cables, 2 Conflector Blocks	Cable: Shielded - SHC68-68-EPM Cable 192061	1-02
	(2m) **Also available: Unshielded	
	Connector Block: Screw Terminals - 77684	4-01
	SCB-68 **Also available: BNC Termination	
	Connector 1:	
	Cable: Shielded - SHC68-68-EPM Cable 192061 (2m) **Also available: Unshielded	1-02
	Connector Block: Screw Terminals- 776844 SCB-68	4-01
	**Also available: BNC Termination	
II PXI-6284	770400 04	
vi PXI-6284 Each NI PXI-6284 requires: 2 Cables, 2 Connector Blocks	779122-01 Connector 0:	
	Cable: Shielded - SHC68-68-EPM Cable 192061 (2m)	1-02
	**Also available: Unshielded	. 04
	Connector Block: Screw Terminals - 776844 SCB-68 **Also available: BNC Termination	1-01
	Connector 1:	
	Cable: Shielded - SHC68-68-EPM Cable 192061	1-02
	(2m) **Also available: Unshielded	
	Connector Block: Screw Terminals - 776844 SCB-68	4-01
NI PCI-6289	**Also available: BNC Termination	
N PCI-6289	779111-01	
Each NI PCI-6289 requires: 2 Cables, 2 Connector Blocks	Connector 0:	
	Cable: Shielded - SHC68-68-EPM Cable 192061 (2m)	1-02
	**Also available: Unshielded	
	Connector Block: Screw Terminals - 776844 SCB-68	4-01

**Also available: BNC Termination

Cable: Shielded - SHC68-68-EPM Cable 192061-02

(2m)

**Also available: Unshielded

Connector Block: Screw Terminals -776844-01

SCB-68
**Also available: BNC Termination

NI PXI-6289

NI PXI-6289

Each NI PXI-6289 requires: 2 Cables, 2 Connector Blocks

779639-01

Connector 0:

Cable: Shielded - SHC68-68-EPM Cable 192061-02

(2m)
**Also available: Unshielded

Connector Block: Screw Terminals -776844-01

SCB-68

**Also available: BNC Termination

Connector 1:

Cable: Shielded - SHC68-68-EPM Cable 192061-02

(2m)
**Also available: Unshielded

Connector Block: Screw Terminals -776844-01 SCB-68

**Also available: BNC Termination

NI PXI-6289 for SCXI Control in PXI/SCXI Combination Chassis

Each NI PXI-6289 for SCXI Control in PXI/SCXI Combination Chassis requires: 2 Cables, 2 Connector Blocks

779123-01

Connector 0:

Cable: Shielded - SHC68-68-EPM Cable 192061-02

(2m)
**Also available: Unshielded

Connector Block: Screw Terminals -776844-01

**Also available: BNC Termination

Connector 1:

Cable: Shielded - SHC68-68-EPM Cable 192061-02

(2m)
**Also available: Unshielded

Connector Block: Screw Terminals -776844-01

**Also available: BNC Termination

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Software Recommendations

LabVIEW Professional **Development System for** Windows



- Advanced software tools for large project development
- Automatic code generation using DAQ Assistant and Instrument I/O Assistant
- · Tight integration with a wide range of
- Advanced measurement analysis and digital signal processing
- Open connectivity with DLLs, ActiveX, and NET objects
- Capability to build DLLs, executables, and MSI installers

NI LabVIEW SignalExpress for Windows



- Quickly configure projects without programming
- Control over 400 PC-based and stand-alone
- Log data from more than 250 data acquisition devices
- Perform basic signal processing, analysis, and file I/O
- Scale your application with automatic LabVIEW code generation
- Create custom reports or easily export data to LabVIEW, DIAdem or Microsoft Excel

NI LabWindows™/CVI for Windows

- · Real-time advanced 2D graphs and charts
- Complete hardware compatibility with IVI, VISA, DAQ, GPIB, and serial
- Analysis tools for array manipulation, signal processing statistics, and curve fitting
- · Simplified cross-platform communication with network variables
- Measurement Studio .NET tools (included in LabWindows/CVI Full only)

NI Measurement Studio **Professional Edition**

- . Support for Microsoft Visual Studio .NET 2010/2008/2005
- Customizable Windows Forms and Web Forms controls for test and measurement user interface design
- · Hardware integration support with data acquisition and instrument control libraries
- Automatic code generation with data acquisition, instrument control, and parameter assistants



The mark LabWindows is used under a license from Microsoft Corporation.



Cross-platform communication with network variables

 Analysis libraries for array operations, signal generation, windowing, filters, signal processing

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Support and Services

System Assurance Programs

NI system assurance programs are designed to make it even easier for you to own an NI system. These programs include configuration and deployment services for your NI PXI, CompactFieldPoint system. The NI Basic System Assurance Program provides a simple integration test and ensures that your system is delivered completely assembled in one box. When you configure your system with the NI Standard System Assurance Program, you can select from available NI system driver sets and application development environments to create customized, reorderable software configurations. Your system arrives fully assembled and tested in one box with your software preinstalled. When you order your system with the standard program, you also receive system-specific documentation including a bill of materials, an integration test report, a recommended maintenance plan, and frequently asked question documents. Finally, the standard program reduces the total cost of owning an NI system by providing three years of warranty coverage and calibration service. Use the online product advisors at ni.com/advisor to find a system assurance program to meet your needs.

Calibration

NI measurement hardware is calibrated to ensure measurement accuracy and verify that the device meets its published specifications. NI offers a number of calibration services to help maintain the ongoing accuracy of your measurement hardware. These services allow you to be completely confident in your measurements, and help you maintain compliance to standards like ISO 9001, ANSI/NCSL Z540-1 and ISO/IEC 17025. To learn more about NI calibration services or to locate a qualified service center near you, contact your local sales office or visit ni com/calibration.

Technical Support

Get answers to your technical questions using the following National Instruments resources.

- Support Visit ni com/support to access the NI KnowledgeBase, example programs, and tutorials or to contact our applications engineers who are located in NI sales offices around the world and speak the local language.
- . Discussion Forums Visit forums.ni.com for a diverse set of discussion boards on topics you care about.
- Online Community Visit community.ni.com to find, contribute, or collaborate on customer-contributed technical content with users like you.

Repair

While you may never need your hardware repaired, NI understands that unexpected events may lead to necessary repairs. NI offers repair services performed by highly trained technicians who quickly return your device with the quarantee that it will perform to factory specifications. For more information, visit ni.com/repair.

Training and Certifications

The NI training and certification program delivers the fastest, most certain route to increased proficiency and productivity using NI software and hardware. Training builds the skills to more efficiently develop robust, maintainable applications, while certification validates your knowledge and ability.

- Classroom training in cities worldwide the most comprehensive hands-on training taught by engineers.
- On-site training at your facility an excellent option to train multiple employees at the same time.
- Online instructor-led training lower-cost, remote training if classroom or on-site courses are not possible.
- Course kits lowest-cost, self-paced training that you can use as reference guides.
- Training memberships and training credits to buy now and schedule training later.

Visit ni.com/training for more information.

Extended Warranty

NI offers options for extending the standard product warranty to meet the life-cycle requirements of your project. In addition, because NI understands that your requirements may change, the extended warranty is flexible in length and easily renewed. For more information, visit ni.com/warranty.

OEM

NI offers design-in consulting and product integration assistance if you need NI products for OEM applications. For information about special pricing and services for OEM customers, visit ni.com/oem.

Alliance

Our Professional Services Team is comprised of NI applications engineers, NI Consulting Services, and a worldwide National Instruments Alliance Partner program of more than 600 independent consultants and integrators. Services range from start-up assistance to turnkey system integration. Visit ni.com/alliance.

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Detailed Specifications

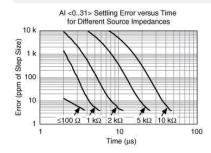
Specifications listed below are typical at 25 °C unless otherwise noted. Refer to the M Series User Manual for more information about NI 62	628x devices.	out NI 628x d	information about	ual for more	ser Manua	Series Us	. Refer to the A	ess otherwise noted	"C unis	at 25 '	typical a	ed below are	Specifications lis	
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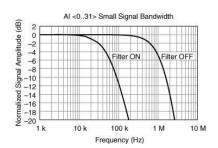
Analog Input	
Number of channels	
NI 6280/6281	8 differential or 16 single ended
NI 6284/6289	16 differential or 32 single ended
ADC resolution	18 bits
DNL	No missing codes guaranteed
NL	Refer to the Al Absolute Accuracy Tables
Sampling rate	
Maximum	625 kS/s single channel, 500 kS/s multi-channel (aggregate)
Minimum	No minimum
Timing accuracy	50 ppm of sample rate
Timing resolution	50 ns
Input coupling	DC
Input range	±10 V, ±5 V, ± 2 V, ±1 V, ±0.5 V, ± 0.2 V, ± 0.1 V
Maximum working voltage for analog inputs (signal + common mode)	±11 V of ALGND
CMRR (DC to 60 Hz)	110 dB
Input impedance	
Device on	
AI+ to AI GND	>10 GΩ in parallel with 100 pF
AI- to AI GND	>10 GΩ in parallel with 100 pF
Device off	
Al+ to Al GND	820 Ω
Al- to Al GND	820 Ω
Input bias current	±100 pA
Crosstalk (at 100 kHz)	
Adjacent channels	-75 dB
Non-adjacent channels	-95 dB
Small signal bandwidth (-3 dB)	750 kHz filter off, 40 kHz filter on
Input FIFO size	2,047 samples
Scan list memory	4,095 entries
Data transfers	
PCI/PXI devices	DMA (scatter-gather), interrupts, programmed I/O
USB devices	USB Signal Stream, programmed I/O
Overvoltage protection (AI <031>, AI SENSE, AI SENSE 2)	
Device on	±25 V for up to eight AI pins
Device off	±15 V for up to eight AI pins
nput current during overvoltage condition	±20 mA max/Al pin

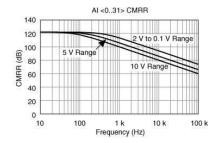
Settling Time for Multichannel Measurements

	Filte	er Off	Filter On
Range	±15 ppm of Step (±4 LSB for Full Scale Step)	±4 ppm of Step (±1 LSB for Full Scale Step)	±4 ppm of Step (±1 LSB for Full Scale Step)
±10 V, ±5 V	2 µs	8 µs	50 μs
±2 V, ±1 V, ±0.5 V	2.5 µs	8 µs	50 µs
±0.2 V, ±0.1 V	3 µs	8 µs	50 µs

Typical Performance Graphs







Number of triggers	1
Source	
NI 6280/6281	AI <0.15>, APFI 0
NI 6284/6289	Al <031>, APFI <01>
Functions	Start Trigger, Reference Trigger, Pause Trigger, Sample Clock, Corwert Clock, Sample Clock Timebase
Source level	
AI <031>	±Full scale
APFI <0.1>	±10 V
Resolution	10 bits, 1 in 1024
Modes	Analog edge triggering, analog edge triggering with hysteresis, and analog window triggering
Bandwidth (-3 dB)	
AI <031>	700 kHz filter off, 40 kHz filter on
APFI <01>	5 MHz
Accuracy	±1%
APFI <01> characteristics	
Input impedance	10 kΩ
Coupling	DC
Protection	
Power on	±30 V
Power off	±15 V

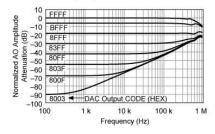
Number of channels	
NI 6280/6284	0
NI 6281	2
NI 6289	4.
DAC resolution	16 bits
DNL	±1 LSB
Monotonicity	16 bit guaranteed
Accuracy	Refer to the AO Absolute Accuracy Table
Maximum update rate	
1 channel	2.86 MS/s
2 channels	2.00 MS/s
3 channels	1.54 MS/s
4 channels	1.25 MS/s
Timing accuracy	50 ppm of sample rate
Timing resolution	50 ns
Output range	Offset \pm reference, includes ± 10 V, ± 5 V, ± 2 V, and ± 1 V calibrated ranges
Offset	0 V, 5 V, APFI <01>, AO <03>1
Reference	10 V, 5 V, 2 V, 1 V, APFI <01>, AO <03>1
Maximum output level	±11 V
Output coupling	DC
Output impedance	0.2 Ω
Output current drive	±5 mA
Overdrive protection	±25 V
Overdrive current	20 mA
Power-on state	±5 mV ²
Power-on glitch	2.3 V peak for 1.2 s
Output FIFO size	8,191 samples shared among channels used
Data transfers	
PCI/PXI devices	DMA (scatter-gather), interrupts, programmed I/O
USB devices	USB Signal Stream, programmed I/O
AO waveform modes:	
Non-periodic waveform Periodic waveform regeneration mode from onboard FIFO Periodic waveform regeneration from host buffer including dynamic update	
Settling time, full scale step 15 ppm (1 LSB)	3 µs
Slew rate	20 V/µs
Glitch energy at midscale transition, ±10 V range	
Magnitude	15 mV
Duration	0.5 µs

 $^{^2}$ For all USB-6281/6289 Screw Terminal devices, when powered on, the analog output signal is not defined until after USB configuration is complete.

External Reference		
APFI <01> characteristics		
Input impedance	10 kΩ	
Coupling	DC	
Protection		

Power on	±30 V
Power off	±15 V
Range	±11 V

AO <0..3> Analog Output External Reference Bandwidth



Calibration (Al and AO) Recommended warm-up time PCI/PXI devices 15 minutes USB devices 30 minutes Calibration interval 2 years

Nomina	al Range	Residual	67 97		Residual	Offset	5092000000		Absolute	
Positive Full Scale	Negative Full Scale	Gain Error (ppm of Reading)	Gain Tempco (ppm/°C)	Reference Tempco	Offset Error (ppm of Range)	Tempco (ppm of Range/°C)	INL Error (ppm of Range)	Random Noise, σ (μVrms)	Accuracy at Full Scale ¹ (µV)	Sensitivity 2 (µV)
10	-10	40	17	1 1	8	11	10	60	980	24
5	-5	45	17	1 1	8	11	10	30	510	12
2	-2	45	17	1	8	13	10	12	210	4.8
1	-1	55	17	1	15	15	10	7	120	2.8
0.5	-0.5	55	17	1 1	30	20	10	4	70	1.6
0.2	-0.2	75	17	1 1	45	35	10	3	39	1.2
0.1	-0.1	120	17	1 1	60	60	10	2	28	0.8

Accuracies listed are valid for up to two years from the device external calibration.

AbsoluteAccuracy = Reading \cdot (GainError) + Range \cdot (OffsetError) + NoiseUncertainty

GainError = ResidualAlGainError + GainTempco · (TempChangeFromLastInternalCal) + ReferenceTempco · (TempChangeFromLastExternalCal)

 $OffsetError = Residual Al OffsetError + OffsetTempco \cdot (TempChangeFromLastInternalCal) + INL_Error$

NoiseUncertainty = $\frac{\text{RandomNoise} \cdot 3}{\sqrt{100}}$ For a coverage factor of 3 σ and averaging 100 points.

¹ Absolute accuracy at full scale on the analog input channels is determined using the following assumptions:

TempChangeFromLastExternalCal = 10 °C

TempChangeFromLastInternalCal = 1 °C

number_of_readings= 100

CoverageFactor = 3 σ

For example, on the 10 V range, the absolute accuracy at full scale is as follows:

GainError = 40 ppm + 17 ppm · 1 + 1 ppm · 10 GainError = 67 ppm

OffsetError = 8 ppm + 11 ppm · 1 + 10 ppm OffsetError = 29 ppm

NoiseUncertainty = $\frac{60 \mu V \cdot 3}{\sqrt{100}}$ NoiseUncertainty = 18 μV

AbsoluteAccuracy = 10 V · (GainError) + 10 V · (OffsetError) + NoiseUncertainty AbsoluteAccuracy = 980 µV

² Sensitivity is the smallest voltage change that can be detected. It is a function of noise.

Nomina	l Range	Residual			Residual	Offset			Absolute	2000
Positive Full Scale	Negative Full Scale	Gain Error (ppm of Reading)	Gain Tempco (ppm/°C)	Reference Tempco	Offset Error (ppm of Range)	Tempco (ppm of Range/°C)	INL Error (ppm of Range)	Random Noise, σ (μVrms)	Accuracy at Full Scale ¹ (µV)	Sensitivity 2 (µV)
10	-10	45	17	1 1	10	11	10	70	1050	28.0
5	-5	50	17	1 1	10	11	10	35	550	14.0
2	-2	50	17	1 1	10	13	10	15	230	6.0
1	-1	60	17	1 1	17	15	10	12	130	4.8
0.5	-0.5	60	17	1 1	32	20	10	10	80	4.0
0.2	-0.2	80	17	1	47	35	10	9	43	3.6
0.1	-0.1	120	17	1 1	62	60	10	9	31	3.6

Accuracies listed are valid for up to two years from the device external calibration.

AbsoluteAccuracy = Reading \cdot (GainError) + Range \cdot (OffsetError) + NoiseUncertainty

GainError = ResidualAlGainError + GainTempco · (TempChangeFromLastInternalCal) + ReferenceTempco · (TempChangeFromLastExternalCal)

OffsetError = ResidualAlOffsetError + OffsetTempco · (TempChangeFromLastInternalCal) + INL_Error

NoiseUncertainty = $\frac{\text{RandomNoise} \cdot 3}{\sqrt{100}}$ For a coverage factor of 3 σ and averaging 100 points.

Absolute accuracy at full scale on the analog input channels is determined using the following assumptions:

TempChangeFromLastExternalCal = 10 °C

TempChangeFromLastInternalCal = 1 °C

number_of_readings= 100

CoverageFactor = 3 o

For example, on the 10 V range, the absolute accuracy at full scale is as follows:

GainError = 45 ppm + 17 ppm · 1 + 1 ppm · 10 GainError = 72 ppm

OffsetError = 10 ppm + 11 ppm · 1 + 10 ppm OffsetError = 31 ppm

NoiseUncertainty = $\frac{70 \mu V \cdot 3}{\sqrt{100}}$ NoiseUncertainty = 21 μV

AbsoluteAccuracy = 10 V · (GainError) + 10 V · (OffsetError) + NoiseUncertainty AbsoluteAccuracy = 1050 μV

² Sensitivity is the smallest voltage change that can be detected. It is a function of noise.

Nominal Range		Nominal Range Residual			Residual	Offset	INL	Absolute
Positive Full Scale	Negative Full Scale	Gain Error (ppm of Reading)	Gain Tempco (ppm/°C)	Reference Tempco	Offset Error (ppm of Range)	Tempco (ppm of Range/°C)	Error (ppm of Range)	Accuracy at Full Scale ¹ (μV)
10	-10	55	15	1	30	12	32	1540
5	-5	60	15	1	30	17	32	820
2	-2	65	25	1	40	30	32	404
1	-1	85	25	1	57	50	32	259

1 Absolute Accuracy at full scale numbers is valid immediately following internal calibration and assumes the device is operating within 10 °C of the last external calibration.

Accuracies listed are valid for up to two years from the device external calibration. AbsoluteAccuracy = OutputValue · (GainError) + Range · (OffsetError)

| | GainError = ResidualGainError + GainTempco - (TempChangeFromLastInternalCal) + ReferenceTempco - (TempChangeFromLastExternalCal)

OffsetError = ResidualOffsetError + AOOffsetTempco · (TempChangeFromLastInternalCal) + INL_Error

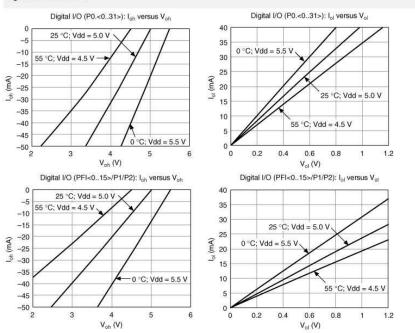
Digital I/O/PFI Static Characteristics Number of channels 24 total 8 (P0.40.7>) 16 (PFI.40.7>/P1, PFI.48.15>/P2)

NI 6284/6289	48 total 32 (P0.<031>) 16 (PFI <07>/P1, PFI <815>/P2)
NO type	5 V TTL/CMOS compatible
Ground reference	D GND
Direction control	Each terminal individually programmable as input or output
Pull-down resistor	50 kΩ typical, 20 kΩ minimum
Input voltage protection ³	±20 V on up to two pins
³ Stresses beyond those listed under <i>Input voltage protection</i> may	cause permanent damage to the device.
Waveform Characteristics (Port 0 Only)	
Terminals used	
NI 6280/6281	Port 0 (P0.<07>)
NI 6284/6289	Port 0 (P0.<031>)
Port/sample size	
NI 6280/6281	Up to 8 bits
NI 6284/6289	Up to 32 bits
Waveform generation (DO) FIFO	2,047 samples
Waveform acquisition (DI) FIFO	2,047 samples
DI Sample Clock frequency	
PCI/PXI devices	0 to 10 MHz ⁴
USB devices	0 to 1 MHz system dependent ⁴
DO Sample Clock frequency	
PCI/PXI devices	
Regenerate from FIFO	0 to 10 MHz
Streaming from memory	0 to 10 MHz system dependent ⁴
USB devices	
Regenerate from FIFO	0 to 10 MHz
Streaming from memory	0 to 1 MHz system dependent ⁴
Data transfers	
PCI/PXI devices	DMA (scatter-gather), interrupts, programmed I/O
USB devices	USB Signal Stream, programmed I/O
DO or DI Sample Clock source ⁵	Any PFI, RTSI, Al Sample or Convert Clock, AO Sample Clock, Ctr n Internal Output, and many other signals
⁴ Performance can be dependent on bus latency and volume of bus ⁵ The digital subsystem does not have its own dedicated internal tir source.	s activity. ming engine. Therefore, a sample clock must be provided from another subsystem on the device or an external
PFI/Port 1/Port 2 Functionality	
Functionality	Static digital input, static digital output, timing input, timing output
Timing output sources	Many AI, AO, counter, DI, DO timing signals
Debounce filter settings	$125\text{ns},6.425\mu\text{s},2.56\text{ms},\text{disable; high and low transitions; selectable per input.}$

Recommended Operation Conditions				
Level	Min	Max		
Input high voltage (V _{IH})	2.2 V	5.25 V		
Input low voltage (V _{IL})	0.0	0.8 V		
Output high current (I _{OH}) P0. <031> PFI <015>/P1/P2	=	-24 mA -16 mA		
Output low current (I _{OL}) P0.<031> PFI <015>/P1/P2	_	24 mA 16 mA		

Level	Min	Max
Positive-going threshold (VT+) Negative-going threshold (VT-)	 0.8 V	2.2 V —
Delta VT hysteresis (VT+ - VT-)	0.2 V	=
I _{IL} input low current (V _{in} = 0 V)		-10 µA
I _{IH} input high current (V _{in} = 5 V)		250 µA

Digital I/O Characteristics



Number of counter/timers	20
Number of countentiners	2
Resolution	32 bits
Counter measurements	Edge counting, pulse, semi-period, period, two-edge separation
Position measurements	X1, X2, X4 quadrature encoding with Channel Z reloading; two-pulse encoding
Output applications	Pulse, pulse train with dynamic updates, frequency division, equivalent time sampling
Internal base clocks	80 MHz, 20 MHz, 0.1 MHz
External base clock frequency	0 MHz to 20 MHz
Base clock accuracy	50 ppm
Inputs	Gate, Source, HW_Arm, Aux, A, B, Z, Up_Down
Routing options for inputs	Any PFI, RTSI, PXI_TRIG, PXI_STAR, analog trigger, many internal signals
FIFO	2 samples

PCI/PCIe/PXI/PXIe devices	Dedicated scatter-gather DMA controller for each counter/timer, interrupts, programmed I/O
USB devices	USB Signal Stream, programmed I/O
Frequency Generator	
Number of channels	1
Base clocks	10 MHz, 100 kHz
Divisors	1 to 16
Base clock accuracy	50 ppm
Output can be available on any PFI or RTSI terminal.	
Phase-Locked Loop (PLL) (PCI/PXI Devices Only)	
Number of PLLs	h
Reference signal	PXI_STAR, PXI_CLK10, RTSI <07>
Dutput of PLL	80 MHz Timebase; other signals derived from 80 MHz Timebase including 20 MHz and 100 kHz Timebases
External Digital Triggers	
Source	Any PFI, RTSI, PXI_TRIG, PXI_STAR
Polarity	Software-selectable for most signals
Analog input function	Start Trigger, Reference Trigger, Pause Trigger, Sample Clock, Convert Clock, Sample Clock Timebase
Analog output function	Start Trigger, Pause Trigger, Sample Clock, Sample Clock Timebase
Counter/timer functions	Gate, Source, HW_Arm, Aux, A, B, Z, Up_Down
Digital waveform generation (DO) function	Sample Clock
Digital waveform acquisition (DI) function	Sample Clock
Device-To-Device Trigger Bus	
°CI devices	RTSI <07> ⁶
PXI devices	PXI_TRIG <07>, PXI_STAR
JSB devices	None
Dutput selections	10 MHz Clock; frequency generator output, many internal signals
Debounce filter settings	$125\text{ns},6.425\mu\text{s},2.56\text{ms},\text{disable};\text{high and low transitions};\text{selectable per input}$
In other sections of this document, RTS/ refers to RTSI <07> for PCI	devices or PXI_TRIG <07> for PXI devices.
Bus Interface	
PCI/PXI devices	3.3 V or 5 V signal environment
JSB devices	USB 2.0 Hi-Speed orfull-speed ^{7,8}
DMA channels (PCI/PXI devices)	 analog input, analog output, digital input, digital output, counter/timer 0, counter/timer 1
USB Signal Stream (USB devices)	 can be used for analog input, analog output, digital input, digital output, counter/timer 0, counter/timer 1
All PXI-628x devices support one of the following features: • May be installed in PXI Express hybrid slots • Or, may be used to control SCXI in PXI/SCXI combo chassis	

Table 1. PXI/SCXI Combo and PXI Express Chassis Compatibility

M Series Device	M Series Part Number	SCXI Control in PXI/SCXI Combo Chassis	PXI Express Hybrid Slot Compatible
PXI-6280	191501C-04	No	Yes
PXI-6281	191501C-03	No	Yes
PXI-6284	191501 C-02	No	Yes

PXI-6289	191501 C-01	No	Yes
	191501C-11	Yes	No
Earlier versions of PXI-628x	191501A-0x 191501B-0x	Yes	No

7 If you are using a USB M Series device in full-speed mode, device performance will be lower and you will not be able to achieve maximum sampling/update rates.

Power Requirements PCI/PXI devices Current draw from bus during no-load condition9 +5 V 0.03 A +3.3 V 0.78 A +12 V 0.40 A -12 V 0.06 A PCI/PXI devices Current draw from bus during AI and AO overvoltage condition9 +5 V 0.03 A +3.3 V 1.26 A +12 V 0.43 A -12 V 0.06 A Caution USB-628x devices must be powered with NI offered AC adapter or a National Electric Code (NEC) Class evice and has appropriate safety certification marks for country of use. USB devices 11 to 30 VDC, 20 W, locking or non-locking power jack with 0.080 in. diameter Power supply requirements center pin, 5/16-32 thread for locking collars

2 A, 250 V

9 Does not include P0/PFI/P1/P2 and +5 V terminals.

Power Limits

Power supply fuse



Caution Exceeding the power limits may cause unpredictable behavior by the device and/or PC/chassis.

PCI devices	
+5 V terminal (connector 0)	1 A max ¹⁰
+5 V terminal (connector 1)	1 A max ¹⁰
PXI devices	
+5 V terminal (connector 0)	1 A max ¹⁰
+5 V terminal (connector 1)	1 A max ¹⁰
P0/PFI/P1/P2 and +5 V terminals combined	2 A max
USB devices	
+5 V terminal	1 A max ¹¹
P0/PFI/P1/P2 and +5 V terminals combined	2 A max

¹⁰ Older revisions have a self-resetting fuse that opens when current exceeds this specification. Newer revisions have a traditional fuse that opens when current exceeds this specification. This fuse is not customer-replaceable, if the fuse permanently opens, return the device to NI for repair.

11 Has a self-resetting fuse that opens when current exceeds this specification.

Physical Requirements		
Printed circuit board dimensions		
NI PCI-6280/6281/6284/6289	10.6 cm x 15.5 cm (4.2 in. x 6.1 in.)	
NI PXI-6280/6281/6284/6289	Standard 3U PXI	
Enclosure dimensions (includes connectors)		

⁸ Operating on a full-speed bus may result in lower performance.

NI USB-6281/6289 Mass Termination	18.8 x 17.09 x 4.45 cm (7.4 x 6.73 x 1.75 in.)
NI USB-6281/6289 Screw Terminal	26.67 x 17.09 x 4.45 cm (10.5 x 6.73 x 1.75 in.)
NI USB-6258/6289 OEM	Refer to the NI USB-622x/625x/628x OEM User Guide
Veight	
NI PCI-6280	151 g (5.3 oz)
NI PCI-6281	158 g (5.6 oz)
NI PCI-6284	159 g (5.6 oz)
NI PCI-6289	167 g (5.9 oz)
NI PXI-6280	218 g (7.7 oz)
NI PXI-6281	225 g (7.9 oz)
NI PXI-6284	229 g (8.1 oz)
NI PXI-6289	237 g (8.4 oz)
NI USB-6281 Mass Termination	1.04 kg (2 lb 4.5 cz)
NI USB-6289 Mass Termination	1.06 kg (2 lb 5.5 cz)
NI USB-6281 OEM	261 g (9.2 oz)
NI USB-6289 OEM	274 g (9.6 oz)
NI USB-6281 Screw Terminal	1.46 kg (3 lb 3.4 cz)
NI USB-6289 Screw Terminal	1.52 kg (3 lb 5.5 oz)
O connector	
NI PCI/PXI-6280/6281	1 68-pin VHDCI
NI PCI/PXI-6284/6289	2 68-pin VHDCI
NI USB-6281 Mass Termination	1 68-pin SCSI
NI USB-6289 Mass Termination	2 68-pin SCSI
NI USB-6281 OEM	1 34-pin IDC, 1 50-pin IDC
NI USB-6289 OEM	2 34-pin IDC, 2 50-pin IDC
NI USB-6281 Screw Terminal	64 screw terminals
NI USB-6289 Screw Terminal	128 screw terminals
ISB-6281/6289 Screw Terminal wiring	16-28 AWG
Maximum Working Voltage ¹²	
6280/6281/6284/6289 channel-to-earth	11 V, Measurement Category I
Caution Do not use for measurements within Categories II, III, or IV.	111, model of the Care gary
² Maximum working voltage refers to the signal voltage plus the common-mode voltage.	
Environmental	
perating temperature	
PCI/PXI devices	0 to 55 °C
USB devices	0 to 45 °C
torage temperature	-20 to 70 °C
lumidity	10 to 90% RH, noncondensing
laximum altitude	2,000 m
ollution Degree (indoor use only)	ž
Shock and Vibration (PXI Devices Only)	
Shock and Vibration (PXI Devices Only) Operational shock	30 g peak, half-sine, 11 ms pulse (Tested in accordance with IEC-60068-2-27. Test profile developed in accordanc with MIL-PRF-28800F.)
	(Tested in accordance with IEC-60068-2-27. Test profile developed in accordance

Nonoperating

5 to 500 Hz, 2.4 g_{rms}

(Tested in accordance with IEC-60068-2-64. Nonoperating test profile exceeds the requirements of MIL-PRF-28800F, Class 3.)

Safety

This product is designed to meet the requirements of the following standards of safety for electrical equipment for measurement, control, and laboratory use:

- IEC 61010-1, EN 61010-1
- UL 61010-1, CSA 61010-1



Note For UL and other safety certifications, refer to the product label or the Online Product Certification section

Electromagnetic Compatibility

This product meets the requirements of the following EMC standards for electrical equipment for measurement, control, and laboratory use:

- EN 61326 (IEC 61326): Class A emissions; Basic immunity
- EN 55011 (CISPR 11): Group 1, Class A emissions
- · AS/NZS CISPR 11: Group 1, Class A emissions
- FCC 47 CFR Part 15B: Class A emissions
- . ICES-001: Class A emissions



Note For the standards applied to assess the EMC of this product, refer to the Online Product Certification section.

Note For EMC compliance, operate this product according to the documentation.



Note For EMC compliance, operate this device with shielded cables.

D

CE Compliance

This product meets the essential requirements of applicable European Directives as follows:

- · 2006/95/EC; Low-Voltage Directive (safety)
- 2004/108/EC; Electromagnetic Compatibility Directive (EMC)

Online Product Certification

Refer to the product Declaration of Conformity (DoC) for additional regulatory compliance information. To obtain product certifications and the DoC for this product, visit ni.com/certification, search by model number or product line, and click the appropriate link in the Certification column.

Environmental Management

NI is committed to designing and manufacturing products in an environmentally responsible manner. NI recognizes that eliminating certain hazardous substances from our products is beneficial not only to the environment but also to NI customers.

For additional environmental information, refer to the NI and the Environment Web page at ni.com/environment. This page contains the environmental regulations and directives with which NI complies, as well as other environmental information not included in this document.

Waste Electrical and Electronic Equipment (WEEE)



EU Customers At the end of their life cycle, all products must be sent to a WEEE recycling center. For more information about WEEE recycling centers and National Instruments WEEE initiatives, visit ni.com/environment/weee.htm.

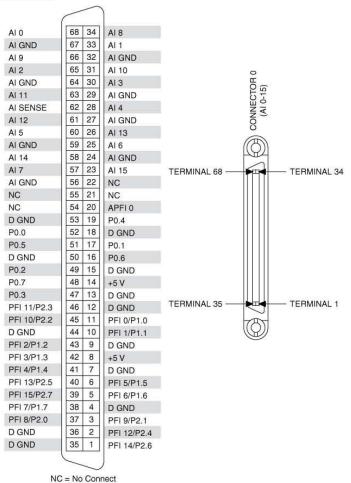
电子信息产品污染控制管理办法 (中国 RoHS)



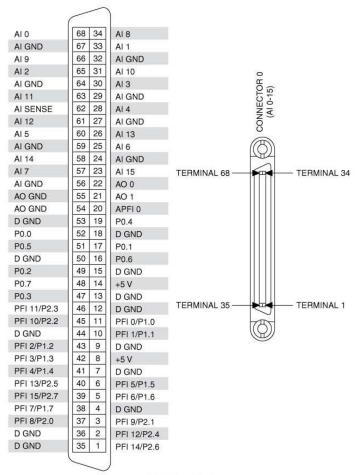
中国客户 National Instruments 符合中国电子信息产品中限制使用某些有害物质指令 (RoHS)。 关于 National Instruments 中国 RoHS 合规性信息、诸登录 ni.com/environment/rohs_china。 (For information about China RoHS compliance, go to ni.com/environment/rohs_china.)

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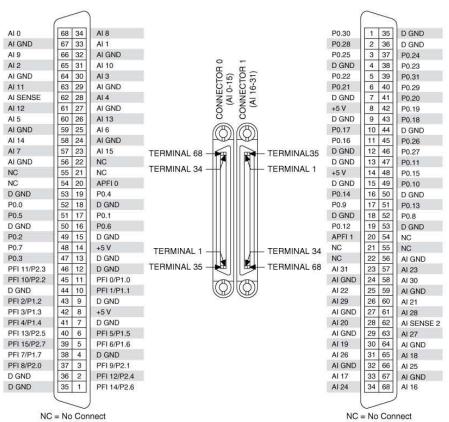
Pinouts/Front Panel Connections



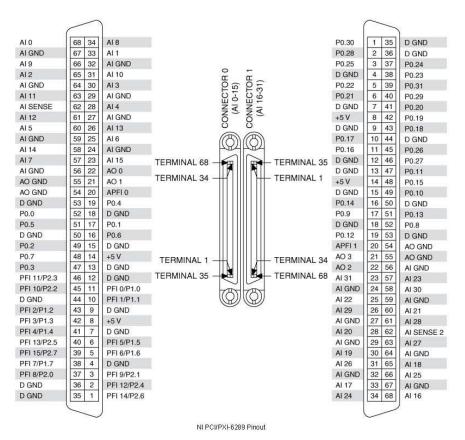
NI PCI/PXI-6280 Pinout



NI PCI/PXI-6281 Pinout



NI PCI/PXI-6284 Pinout



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APPENDIX C. PACIFIC INSTRUMENTS MODEL 6100/6160



MODEL 6100/6160 PROGRAMMABLE TRANSDUCER AMPLIFIERS

FEATURES

- Voltage & current excitation with remote sensing
- Isolated excitation and input
- 300 Volts common mode
- Automatic zero and balance
- Resistive or DAC shunt calibration
- Gains 1 to 5,000
- 50 kHz Bandwidth, 100 kHz optional
- Six-pole, low-pass filter
- Dual analog outputs
- Program monitoring of output and excitation



INPUT ISOLATED TRANSDUCER SIGNAL CONDITIONING

Series 6100 is an automated, transducer signal conditioning amplifier system. The basic mainframe holds 32 channels, which is expandable to 1,024 channels. It is available with RS-232, IEEE-488, USB or Ethernet interface and software for Windows 2000 and XP.

The 6160 is a two-channel transducer amplifier-filter module. Each channel has isolated input and excitation, 50 kHz bandwidth and two outputs that can be filtered or wideband. Bandwidth of 100 kHz is optional.

The bridge input is ten-wire shielded; input (2), excitation (2), sense (2) and shunt calibration (4) with programmable constant voltage or constant current excitation. Programmable bridge completion eliminates plug-in jumpers, loose resistors and component soldering. Automatic bridge balancing ahead of the instrumentation amplifier accommodates large unbalances without limiting gain or dynamic range.

The input and excitation are isolated from the outputs, power and control interface. This gives the user complete freedom to ground the input transducer without creating ground loops that introduce noise and offset errors. The isolation provides for operation with up to ±300 Volts of common mode applied to the input.

The differential instrumentation amplifier has programmable gains from 1 to 5,000 and automatic zero. The standard filter is a six-pole Bessel with four programmable bandwidths and wideband. An optional four-pole Bessel filter has continuously programmable bandwidth with 1 Hz resolution below 1 kHz and 5 Hz above 1 kHz. Each channel has two buffered, ±10 Volt outputs. The output and excitation can be digitally monitored using any of the supported interfaces.

A "features card" provides shunt calibration using dedicated inputs. The standard is two-step, resistive shunt calibration that may be applied by program selection to internal or external bridge arms. Four-step resistive shunt calibration and shunt calibration using a DAC with 16-bit resolution are also available. Voltage substitution employing an external, traceable standard is provided for gain calibration. Automatic zero and gain calibration are implemented in PI610 software.

The mainframe interfaces are IEEE-488, RS-232, Ethernet and USB 2.0. The basic 6100 has both the IEEE-488 and RS-232 interfaces. The the 6000U has a USB 2.0 interface. Ethernet interface is provided using an adapter. Previous programmed operating parameters and the balance and calibration settings are automatically loaded during power-up and by Reset.

User programming is facilitated by a high-level instruction set that is present in the mainframe or USB driver. The 6160 is programmed by text strings sent from the user's application. Optional Windows application software, PI610, is fully configured and ready to use. It provides menu programming of operating parameters or can download parameters from an Access compatible database file. It includes a window that graphically displays amplifier excitation voltage and current and output. PI610 may also be used as a component module DLL with LabView, Visual Basic, Excel or other windows programming language to design custom control and operator interfaces.

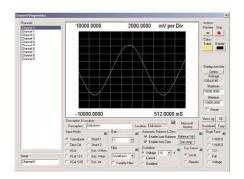
Panel60 is maintenance and calibration software for all Series 6000 and 6100 products. It is a beneficial tool that enables the technician to verify amplifier settings and configuration and make adjustments to gain, zero, balance and other calibrated parameters. A calibration system, ACS2000, automatically calibrates amplifier gain and excitation and certifies the amplifier to the published specification with an archived record of measured performance.





CHANNEL MODULES

- Isolated input and excitation for use with grounded transducers
- Programmable voltage or current excitation with remote sensing
- Programmable bridge completion, no jumpers or rewiring to change gage types
- Versatile 10-wire shielded input handles all gages
- High-resolution gain and excitation programming
- Two or four-step shunt, DAC simulated shunt and voltage substitution calibration
- Automatic balance, zero and calibration make test setup quick and easy
- Test connector on front of module gives access to excitation, sense, inputs and output.



SYSTEM

- Fully programmable, no manual controls
- Thirty-two channels per enclosure, up to 1,024 channels per system
- Programmed operating parameters are automatically loaded at power-up
- Two sets of high and low-level alarms with the capability for controlling external equipment
- Integral tray routes input and output cables to exit from the rear
- Choice of IEEE-488, RS232, USB 2.0 or Ethernet interface for programming and control
- Automatic calibration system, ACS2000, provides fast and automated calibration and certification to traceable standards.



PI610 SOFTWARE

- Ready to run or component module DLL software
- Design a custom GUI using Visual Basic, LabView, Access or Excel
- Use spreadsheet, database or built-in screens to program channel settings
- Copy function makes adding channels quick and easy
- Simplify calibration using automatic procedures.
- Controls external voltage standard for traceable gain calibration
- Real-time graphical display of excitation and output is useful for detecting installation problems



CONSTANT VOLTAGE	Linearity
VoltageProgrammable from 0.1 to 20 Volts with 0.5 mV resolution. Calibrated 2-Volt steps ±0.1%.	and higher. Common Mode60 dB plus gain in dB to 120 dB for balanced
Remote SenseProgrammable local or remote sense, sense cur- rent less than 10 uA.	input and 110 dB for a 350 Ohm source unbal- ance, DC to 60 Hz.
Current	CM Voltage±300 Volts operating.
Regulation±0.01% over input voltage range and no-load to full-load.	ZeroAutomatic zero to ±2 μV RTI or ±1.0 mV RTO whichever is greater.
Stability±0.01% for 30 days. Temperature coefficient less than ±0.005%/°C	Zero Stability±5 μV RTI, ±1 mV RTO at constant temperature, ±1 μV RTI, ±0.2 mV RTO/°C.
Noise	Source Current±25 nA, ±0.05 nA°C.
MonitorExcitation voltage or current is read by a program instruction. Accuracy is ±0.2%.	Noise (10 kHz)2.0 μV RTI plus 0.3 mV RTO, RMS. Bandwidth50 kHz (-3 dB) for gains 1 to 1,000, 20kHz (-3 dB) for gains above 1,000.
CONSTANT CURRENT	Bandwidth (HF)100 kHz (-3 dB) for gains 1 to 1,000, 50 kHz
Output RangeProgrammable 0.1mA to 51.2 mA with 1 µA reso- lution. Calibrated 5 mA steps ±0.1%.	(-3 dB) for gains above 1,000. Slew Rate
Compliance0.1 to 20 Volts.	Overload Recovery120 µS to within ±0.1% for a 10 times overload to
Regulation±0.01% or ±0.1μA for 10% line change. Noise	±10 Volts.
Stability	MonitorOutput is read by a program instruction. Resolutio is ±0.003%.
MonitorExcitation voltage or current is read by a program instruction. Accuracy is ±0.2%.	OutputTwo ±10 Volt full scale buffered outputs. Each may be program selected for filtered or wideband response.
INPUT - BRIDGE	FILTER (STANDARD)
Configuration	TypeSix-pole, low-pass Bessel (36 dB/octave).
sense (2) and shunt calibration (4). Programmable bridge completion for half bridges and 120 Ohm	FrequencyFour programmable filter bandwidths, 150 Hz, 625 Hz, 10 kHz and wideband.
and 350 Ohm quarter bridges. Other gage resist- ances by request.	Frequency (HF)Four programmable filter bandwidths, 300 Hz, 1.25 kHz, 5 kHz, 20 kHz and wideband.
Bridge BalanceAutomatic by program control. Balance accuracy ±0.05% of range, ±1 mV RTO. Stability ±0.02%	FILTER (OPTIONS)
for 8 hours, ±0.005%/°C. Range set by resistor up	TypeFour-pole, low-pass Bessel (24 dB/octave)
to 25 mV/V, 2.5 mV/V (350 Ohms) installed.	Freq. (PFBE2)4 Hz to 1 kHz, 1 Hz resolution, 1 kHz to
Impedance50 Megohms, shunted by 500 pF.	10 kHz, 5 Hz resolution, ±2% accuracy.
Protection±50 Volts, differential and ±350 Volts common mode.	Freq. (PHFBE2)10 Hz to 1 kHz, 1 Hz resolution, 1 kHz to 20 kHz, 5 Hz resolution, ±2% accuracy.
CALIBRATION	INTERFACE CONNECTORS
Shunt (Standard)Two steps of single shunt. Calibration resistors are installed on terminals. Program selection of inter- nal or external shunt connection.	All connectors for input and output of analog and control signals are mounted on the front edge of the 6160 module. All mating connec- tors, except BNC type, are furnished.
Shunt ResistorsInstalled shunt resistors provide 0.502 and 0.250, ±1% mVV for 350 Ohm bridge. Customer speci-	TransducerEach channel has a 15-pin Type D input connector
fied, 0.01% shunt resistors are available. Voltage	Output
Programmable 1, 0.1 and 0.01, attenuation with ±0.02% accuracy. Attenuator output may be con-	Test
nected to bus for external monitoring. Zero CalibrationAmplifier input disconnected and shorted for zero	ENCLOSURES AND INTERFACE The rack enclosures provide slots for 16 modules, 32 channels using
calibration. CALIBRATION OPTIONS	the 6160. They contain a channel controller and power supply that
Shunt (S4)Four-steps of single shunt. Calibration resistors installed on terminals. May be wired for local	operates on 115 or 230 VAC. The basic 6100 Mainframe enclosure includes IEEE-488 and RS232 interfaces. One 6100 mainframe will control up to thirty-one 6001 slave enclosures. Ethernet is provided
shunt at the input connector. Sim Shunt (DAC)A programmable DAC referenced to the excitation	by an adapter on the 6100. The 6100U has a USB 2.0 interface. USB hubs are used to support multiple 6100U enclosures.
voltage applies simulated shunt. Two precision range resistors program selected. Resolution is	INDICATORS Payr/Adv Indicates power is applied to the appleques Plijele
0.0015% (16-bits) AMPLIFIER	Pwr/AdrIndicates power is applied to the enclosure. Blink when a channel in the enclosure is being addresse by a program instruction.
Range±2 mV to ±10 Volts full scale. Gain	ResetIndicates that enclosure reset is being asserted.
resolution.	CalibrationIndicates that one or more channels are in a calibration mode.
Gain Steps	
2,000, 3,000 and 5,000 with ±0.05% accuracy. Gain Stability±0.02% for 30 days, ±0.005%/°C.	



PROGRAM IN	STRUCTIONS
The following programming a	program instructions are provided to implement system and operation.
Address	Selects single channel or group of channels for subsequent programming.
Reset	Stops any operation in process, sets all programmable parameters to the stored settings.
Gain	Program gain of channel, followed by autozero.
Filter	Program filter steps and wideband for a chan- nel, followed by autozero.
Auto-Balance	Initiate automatic balance, preceded by autozero:
Cal Enable	Enables or disables selected calibration mode.
Calibration	Selects calibration mode and step.
Excitation	Select voltage or current excitation, set voltage or current level and select remote or local sens- ing.
Verification	Read back channel status and parameters.
Read Excitation	onReturns value of excitation voltage or current.
Read Output	Return value of channel output.

PHYSICAL

MODULE

Size	0.8 inch wide by 9 inches high by 9 inches deep.
Weight	Approximately 13 oz.
Mounting	The module slides into the enclosure on card guides accessed through the front door and is secured by locking extractors. Rear access is not required to change modules or input and output connectors

RACK ENCLOSURE (Master & Slave)

Module Slots	16

Module Slots	16
Cable Tray	A built-in tray routes input and output cables to exit from the rear of the enclosure.
Cooling	
Size	19 inches wide by 14 inches tall by 23 inches deep (including mating connectors).
Weight	Approximately 60 pounds, with all modules installed.
Power	115 or 230 VAC +10% 47 to 63 Hz

ENVIRONMENTAL

Temperature	Operating, 0°C to +50°C.
Humidity	95% without condensation.
Shock/Vibration	Normal shipping and handling of laboratory
	instruments.

CALIBRATION SYSTEM
Pacific Instruments Model ACS2000, Automated Calibration
System will align, calibrate and certify Series 6000 analog input modules to factory or user performance specifications. A fully automated, PC controlled test station it has the flexibility to run a single performance test or complete calibration and certification procedures. Measured performance data is archived by unit serial number. A print utility generates hard copy test reports.

ORDERING INFORMATION

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ш	ш	'n	v	15

× 100	bandwidth,		diripinior,	00 11112
6160HF			amplifier,	100 kHz
	bandwidth,	200 kS/s.		

OPTIONS

6000-PFBE2	.Continuously	programmable	filter,	4 Hz to
	10 kHz.			
6000-PHFBE2	Continuously	programmable	filter,	10 Hz to

6060-DAC .DAC controlled simulated shunt. 6060-S4 .Four-step shunt calibration.

EMPLOSOME	.3
6100	Mainframe enclosure, 16 slot with IEEE-488 and RS232 interfaces.
6100U	Mainframe enclosure, 16-slot with USB 2.0 programming and control interface.
6101	Slave enclosure, 16-slot. Used with 6000 mainframes.

ENCLOSURE OPTIONS

	Remote connector panel with 15-pin, ¼ turn twist lock MIL type input connectors and BNC output connectors. Mating input connectors are furnished. Cable length is 2 meters.
	Ethernet adapter for 6100 Mainframe.
6087-6060 SOFTWARE	Test fixture with 1 meter cable.
	Operating software for Windows 2000/XP.

.Maintenance and calibration software for Windows 2000/XP. PANEL60 ...

CALIBRATION SYSTEM ACS2000. .Calibration & certification system with fixture for Model 6060.



6087-6060 Test Fixture

Attached to the test connector on the 6060 module it provides test points for: Transducer input, amplifier input, shunt calibration, excita-tion output, excitation sense and amplifier output

APPENDIX D. PACIFIC INSTRUMENTS MODEL 6100/6165



MODEL 6100/6165 PROGRAMMABLE INSTRUMENTATION AMPLIFIERS

FEATURES

- Isolated input
- 300 Volts common mode
- Automatic zero
- Gains 1 to 5,000
- Voltage Substitution Calibration
- 50 kHz Bandwidth, 100 kHz optional
- Six-pole, low-pass filter
- Dual analog outputs
- Program monitoring of output



INPUT-ISOLATED INSTRUMENTATION AMPLIFIER

Series 6100 is an automated, transducer signal conditioning amplifier system. The basic mainframe holds 32 channels, which is expandable to 1,024 channels. It is available with RS-232, IEEE-488, USB or Ethernet interface and software for Windows 2000 and XP.

The 6165 is a two-channel amplifier-filter module. Each channel has isolated input, 50 kHz bandwidth and two outputs that can be filtered or wideband. Bandwidth of 100 kHz is optional.

The input is two-wire shielded and is isolated from the outputs, power and control interface. This gives the user complete freedom to ground the input without creating ground loops that introduce noise and offset errors. The isolation provides for operation with up to ±300 Volts of common mode applied to the input.

The differential instrumentation amplifier has programmable gains from 1 to 5,000 and automatic zero. The standard filter is a six-pole Bessel with four programmable bandwidths and wideband. An optional four-pole Bessel filter has continuously programmable bandwidth 1 Hz resolution below 1 kHz and 5 Hz above 1 kHz. Each channel has two buffered, ±10 Volt outputs. The output can be digitally monitored using any of the supported interfaces.

Voltage substitution calibration, employing an external standard, is provided for gain calibration. Automatic zero and gain calibration are implemented in PI610 software.

The mainframe interfaces are IEEE-488, RS-232, Ethernet and USB 2.0. The 6100 has both the IEEE-488 and RS-232 interfaces. The the 6000U has a USB 2.0 interface. Ethernet interface can be provided using an adapter. Previous programmed operating parameters and the calibration settings are automatically loaded during power-up and by Reset.

User programming is facilitated by a high-level instruction set that is present in the mainframe or USB driver. The 6160 is programmed by text strings sent from the user's application. Optional Windows application software, Pl610, is fully configured and ready to use. It provides menu programming of operating parameters or can download parameters from an Access compatible database file. It includes a window that graphically displays the amplifier output. Pl610 may also be used as a component module DLL with LabView, Visual Basic, Excel or other windows programming language to design custom control and operator interfaces.

Panel60 is maintenance and calibration software for all Series 6000 and 6100 products. It is a beneficial tool that enables the technician to verify amplifier settings and configuration and make adjustments to gain, zero and other calibrated parameters. A calibration system, ACS2000, automatically calibrates amplifier gain and certifies the amplifier to the published specification with an archived record of measured performance.





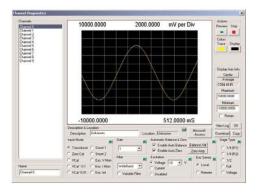
SYSTEM

- Fully programmable, no manual controls
- Thirty-two channels per enclosure, up to 1,024 channels per system
- Programmed operating parameters are automatically loaded at power-up
- Integral tray routes input and output cables to exit from the rear
- Choice of IEEE-488, RS232, USB 2.0 or Ethernet interface for programming and control
- Automatic calibration system, ACS2000, provides fast and automated calibration and certification to traceable standards.

CHANNEL MODULES

- Two channels per module
- Isolated input for use with grounded sources
- 300 Volt operating common mode
- High-resolution gain programming
- Highest accuracy, <0.05% for gain 1,000
- Voltage substitution calibration
- Automatic zero and calibration make test setup quick and easy
- Six-pole anti-alias filter
- Dual buffered outputs, digital output monitor
- Two sets of high and low-level alarms





PI610 SOFTWARE

- Ready to run or Application Programmers software
- Design a custom GUI using Visual Basic, LabView, Access or Excel
- Use spreadsheet, database or built-in screens to program channel settings
- Copy function makes adding channels quick and
- Simplify calibration using automatic procedures.
- Controls external voltage standard for traceable gain calibration
- Real-time monitor graphically displays amplifier output



INPUT	INTERFACE CONNECTORS
Configuration2 wire plus shield	All connectors for input and output of analog and control signals are
Impedance	mounted on the front edge of the 6165 module. All mating connec-
Protection±50 Volts, differential and ±350 Volts common	tors, except BNC type, are furnished.
mode	[
	InputEach channel has a 15-pin Type D input connector
CALIBRATION	OutputBoth outputs for both channels in a 9-pin Type D
VoltageAlternate input for external calibration source.	connector.
Programmable 1, 0.1 and 0.01, attenuation with	ENCLOSURES AND INTERFACE
±0.02% accuracy. Attenuator output may be con-	The rack enclosures provide slots for 16 modules, 32 channels using
nected to bus for external monitoring.	the 6165. They contain a channel controller and power supply that
Zero CalibrationAmplifier input disconnected and shorted for zero	operates on 115 or 230 VAC. The basic 6100 Mainframe enclosure
calibration.	includes IEEE-488 and RS232 interfaces. One 6100 mainframe will
AMPLIFIER	control up to thirty-one 6001 slave enclosures. Ethernet is provided
	by an adapter on the 6100. The 6100U has a USB 2.0 interface.
Range±2 mV to ±10 Volts full scale.	USB hubs are used to support multiple 6100U enclosures.
GainProgrammable from 1 to 5,000 with 0.05%	
resolution.	INDICATORS
Gain Steps	Pwr/AdrIndicates power is applied to the enclosure. Blinks
5, 10, 20, 30, 50, 100, 200, 300, 500, 1,000,	when a channel in the enclosure is being addressed
2,000, 3,000 and 5,000 with ±0.05% accuracy.	
	by a program instruction.
Gain Stability±0.02% for 30 days, ±0.005%/°C.	ResetIndicates that enclosure reset is being asserted.
Linearity±0.01% for gains < 1000, ±0.02% for gain 1000	CalibrationIndicates that one or more channels are in a cali-
and higher.	bration mode.
Common Mode60 dB plus gain in dB to 120 dB for balanced	
input and 110 dB for a 350 Ohm source unbal-	PROGRAM INSTRUCTIONS
ance, DC to 60 Hz.	The following program instructions are provided to implement system
	programming and operation.
CM Voltage±300 Volts operating.	AddressSelects single channel or group of channels for
ZeroAutomatic zero to ±2 μV RTI or ±1.0 mV RTO	subsequent programming.
whichever is greater.	
Zero Stability±5 µV RTI, ±1mV RTO at constant temperature,	ResetStops any operation in process, sets all pro-
±1 µV RTI, ±0.2 mV RTO/°C.	grammable parameters to the stored settings.
	GainProgram gain of channel, followed by autozero.
Source Current±25 nA, ±0.05 nA°C.	FilterProgram filter steps and wideband for a chan-
Noise (10 kHz)2.0 μV RTI plus 0.3 mV RTO, RMS.	nel, followed by autozero.
Bandwidth	AND THE ADMINISTRATION OF THE PROPERTY OF THE
(-3 dB) for gains above 1,000.	Auto-ZeroNulls the outputs with the input disconnected
	and shorted.
Bandwidth (HF)100 kHz (-3 dB) for gains 1 to 1,000, 50 kHz	Cal EnableEnables or disables selected calibration mode.
(-3 dB) for gains above 1,000.	CalibrationSelects calibration mode and step.
Slew Rate	VerificationRead back channel status and parameters.
Overload Recovery120 µS to within ±0.1% for a 10 times overload to	
±10 Volts	Read OutputReturn value of channel output.
MonitorOutput is read by a program instruction. Resolution	
is ±0.003%.	
OutputTwo ±10 Volt full scale buffered outputs. Each may	
be program selected for filtered or wideband	
response.	
FILTER (STANDARD)	
TypeSix-pole, low-pass Bessel (36 dB/octave).	
FrequencyFour programmable filter bandwidths, 150 Hz, 625	
Hz, 2.5 kHz, 10 kHz and wideband.	
Frequency (HF)Four programmable filter bandwidths, 300 Hz,	
1.25 kHz, 5 kHz, 20 kHz and wideband.	
FILTER (OPTIONS)	
Type	
Freq. (PFBE2)4 Hz to 1 kHz, 1 Hz resolution, 1 kHz to	
10 kHz, 5 Hz resolution, ±2% accuracy.	
Freq. (PHFBE2)10 Hz to 1 kHz, 1 Hz resolution, 1 kHz to	
20 kHz, 5 Hz resolution, ±2% accuracy.	



PHYSICAL	OR
MODULE	MOD
Size0.8 inch wide by 9 inches high by 9 inches deep.	6165
WeightApproximately 13 oz.	6165
MountingThe module slides into the enclosure on card guides accessed through the front door and is secured by locking extractors. Rear access is	<u>0PTI</u>
not required to change modules or input and	5550
output connectors.	6000
RACK ENCLOSURE (Master & Slave)	
Module Slots16.	ENC
Cable Tray	6100
CoolingBuilt-in fan with replaceable filter.	6100
Size	6101
Weight Approximately 60 pounds, with all modules	
installed.	ENC
Power	6000
ENVIRONMENTAL	SOFT
Temperature Operating, 0°C to +50°C.	PI61
Humidity95% without condensation.	01
Shock/VibrationNormal shipping and handling of laboratory instruments.	PANE
CALIBRATION SYSTEM	CALI
Pacific Instruments Model ACS2000, Automated Calibration	ACS2
System will align calibrate and cortify Sories 6100 analog	

Pacific Instruments Model ACS2000, Automated Calibration System will align, calibrate and certify Series 6100 analog input modules to factory or user performance specifications. A fully automated, PC controlled test station, it has the flexibility to run a single performance test or complete calibration and certification procedures. Measured performance data is archived by unit serial number. A print utility generates hard copy test reports.

ORDERIN MODULE	ORDERING INFORMATION		
6165	Two-channel instrumentation amplifier, 50 kHz bandwidth, 100 kS/s.		
6165HF	Two-channel instrumentation amplifier, 100 kHz bandwidth, 200 kS/s.		
OPTIONS			
6000-PFBE2	Continuously programmable filter, 4 Hz to 10 kHz.		
6000-PHFBE2.	Continuously programmable filter, 10 Hz to 20 kHz.		
ENCLOSURES			
6100	Mainframe enclosure, 16-slot with IEEE-488 and RS232 interfaces.		
6100U	Mainframe enclosure, 16-slot with USB 2.0 programming and control interface.		
6101	Slave enclosure, 16-slot. Used with 6000 mainframes.		
ENCLOSURE OF	PTIONS		
6000-E	Ethernet adapter for 6100 Mainframe.		
SOFTWARE			
PI610	Operating software for Windows 2000/XP. Supplied as a turnkey application and DLL.		
PANEL60	Maintenance and calibration software for Windows 2000/XP.		
CALIBRATION S	SYSTEM		
ACS2000	Calibration & certification system with fixture for Model 6165.		

NOMENCLATURE

ADC Analog-to-digital converter

dB Decibels FS Full scale

G Gain mV Millivolts

nA Nano amperes

NI National Instruments

NIST National Institute of Standards and Technology

psia Pounds square inch absolute

rms Root mean square rss Root sum square RTI Relative to input RTO Relative to output

U₉₅ 95% interval for measurement uncertainty

V Volts

 σ Standard deviation Δ Delta or difference

μV Microvolts